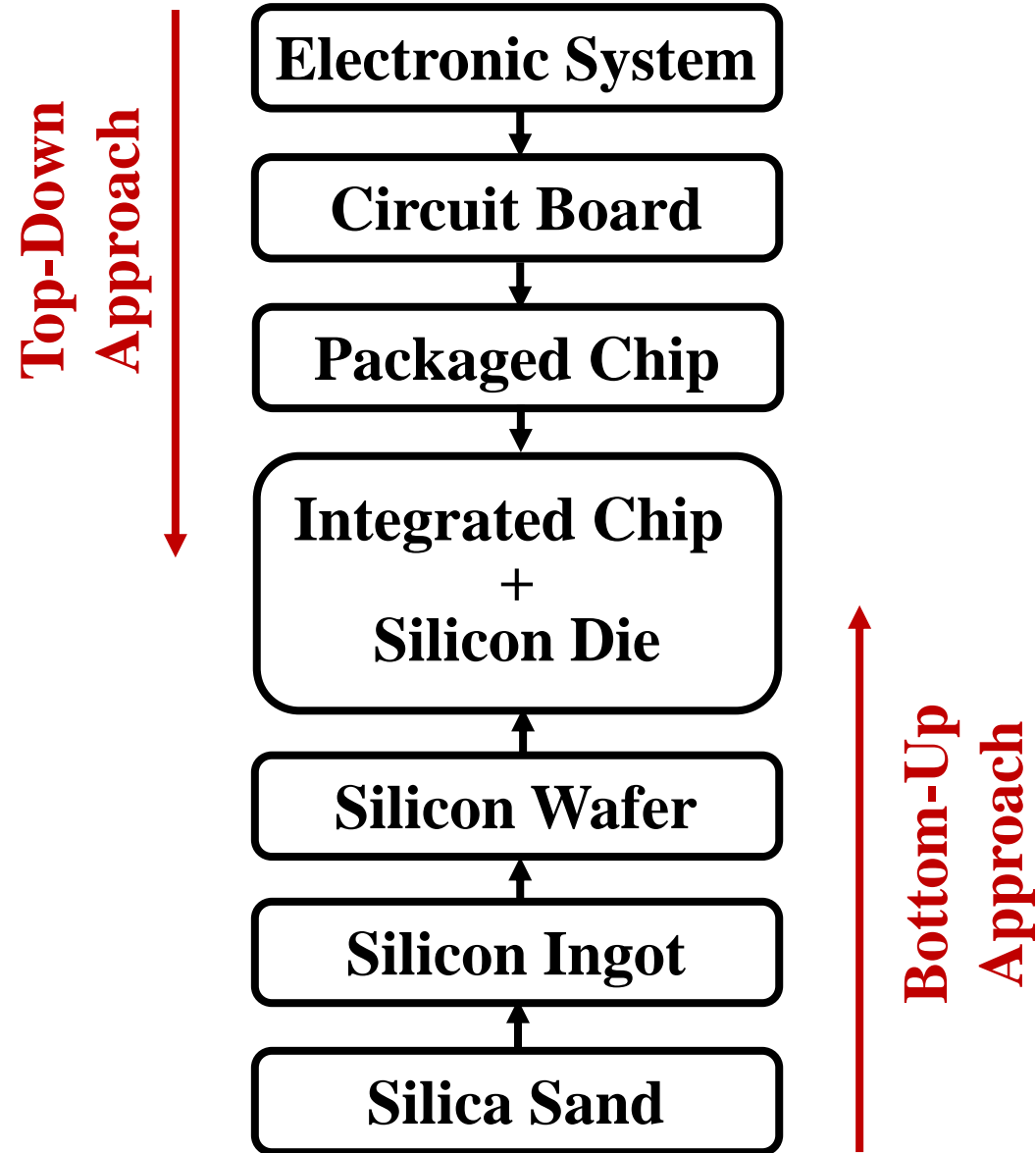


# **Broad View of VLSI Design and CMOS Manufacturing Process**

**Santunu Sarangi**

# Broad View of VLSI Design



# Electronic System

Top-Down  
Approach

Electronic System

Circuit Board

Packaged Chip

Integrated Chip  
+  
Silicon Die

Silicon Wafer

Silicon Ingot

Silica Sand

Bottom-Up  
Approach

Computer



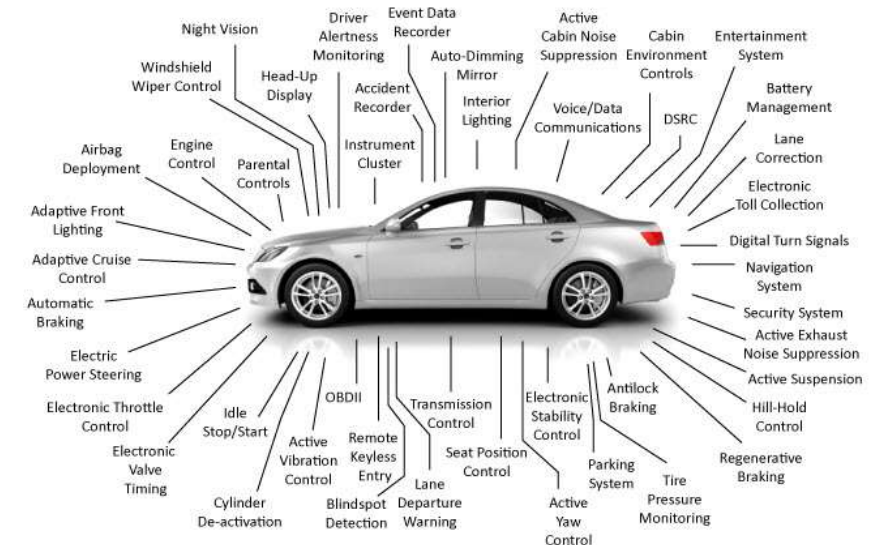
Smart phone



Smart Watch



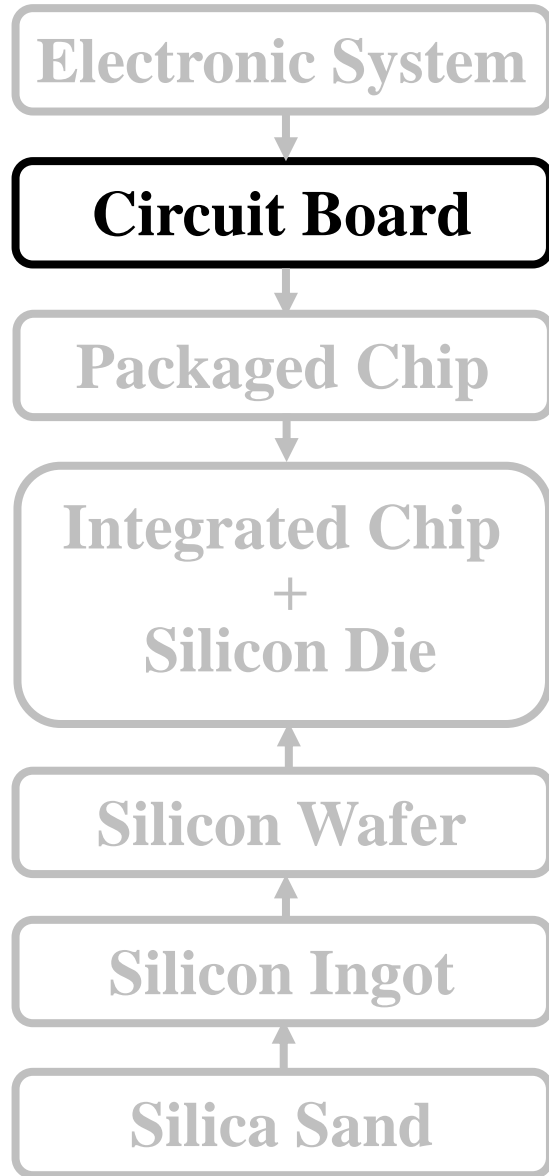
Automotive Electronics



# Circuit Board

Top-Down  
Approach

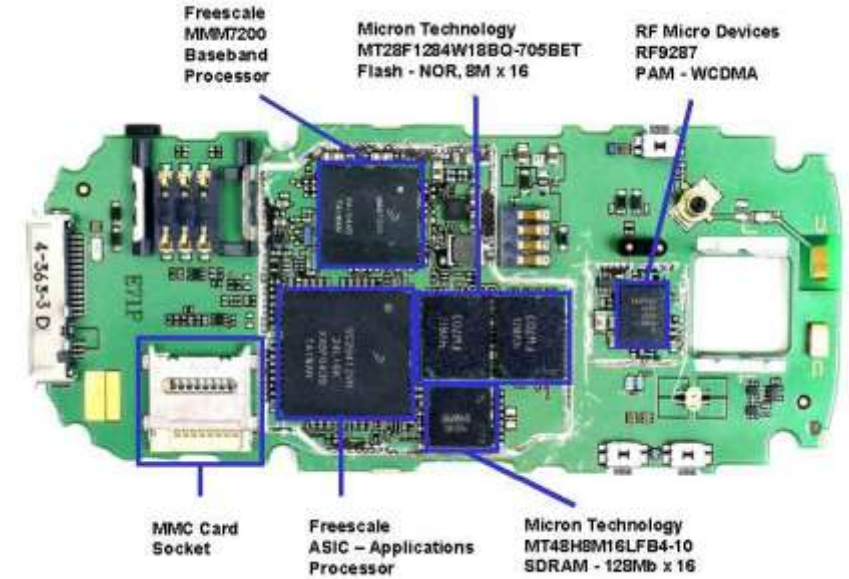
Bottom-Up  
Approach



Mother board

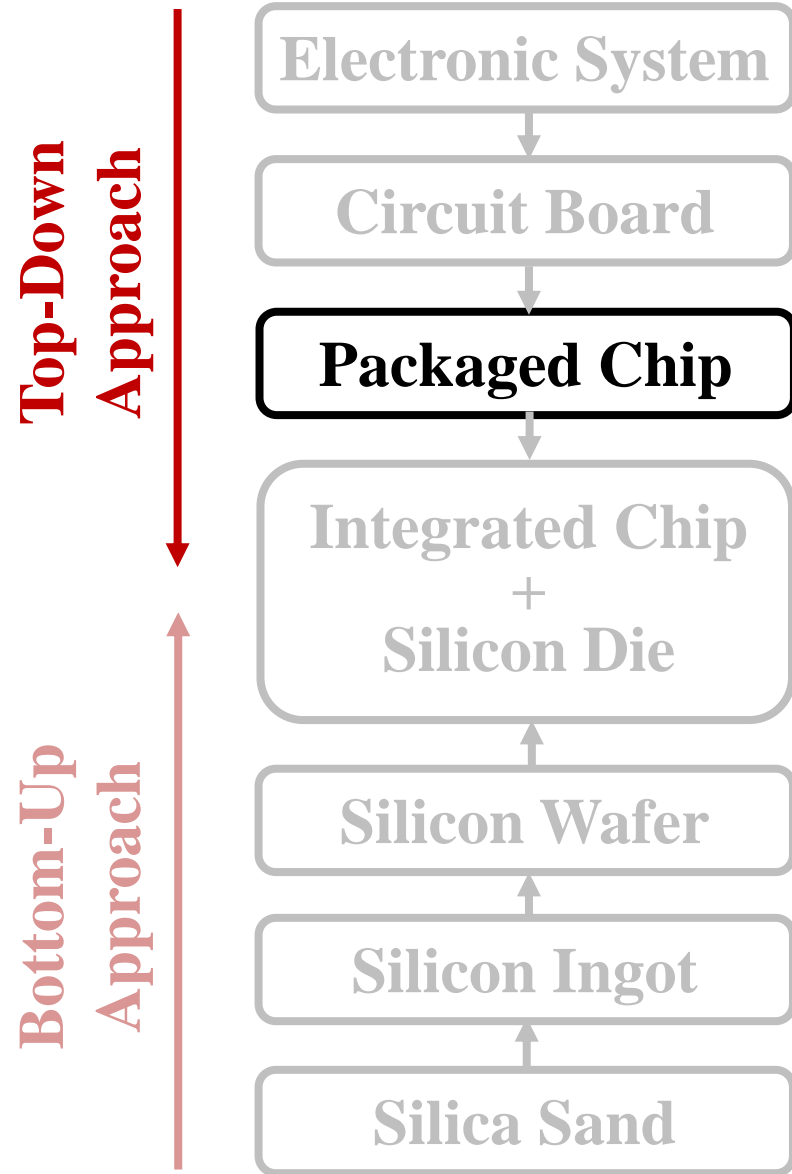


Mobile board



Automotive Car PCB

# Packaged Chip



Packaged Chip



Micro Processor





# Integrated Chip and Silicon Die

Top-Down  
Approach

Bottom-Up  
Approach

Electronic System

Circuit Board

Packaged Chip

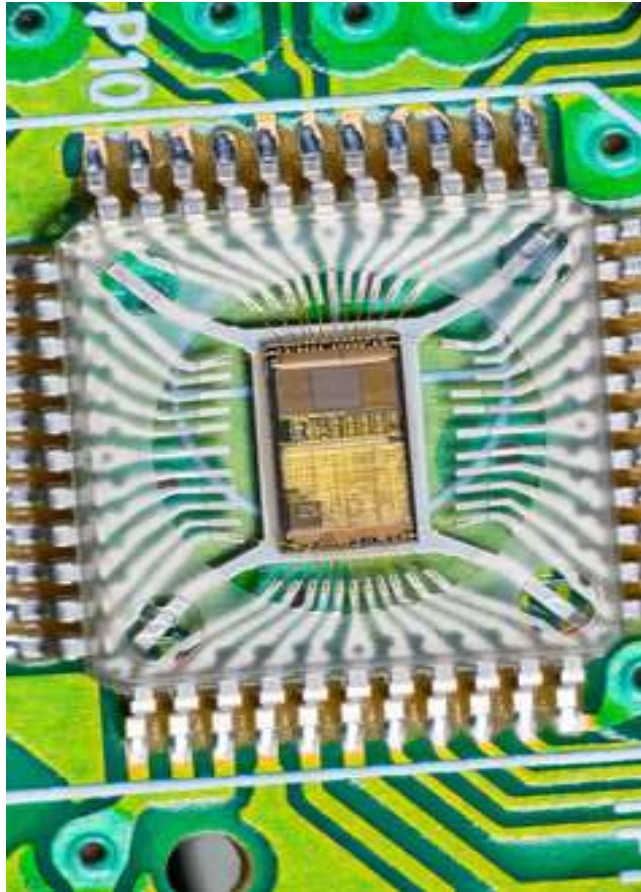
**Integrated Chip  
+  
Silicon Die**

Silicon Wafer

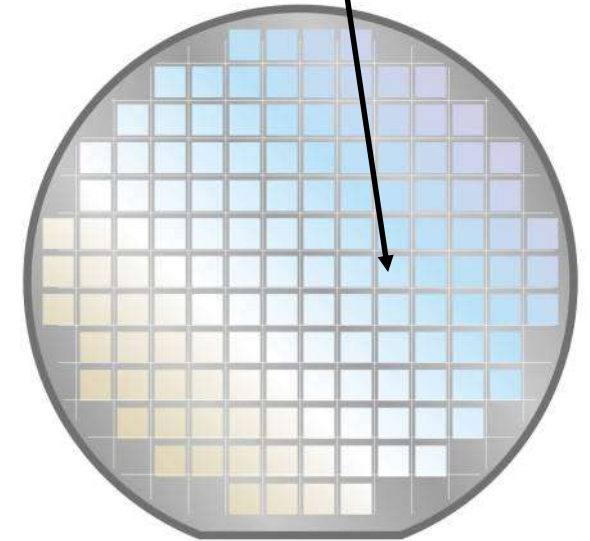
Silicon Ingot

Silica Sand

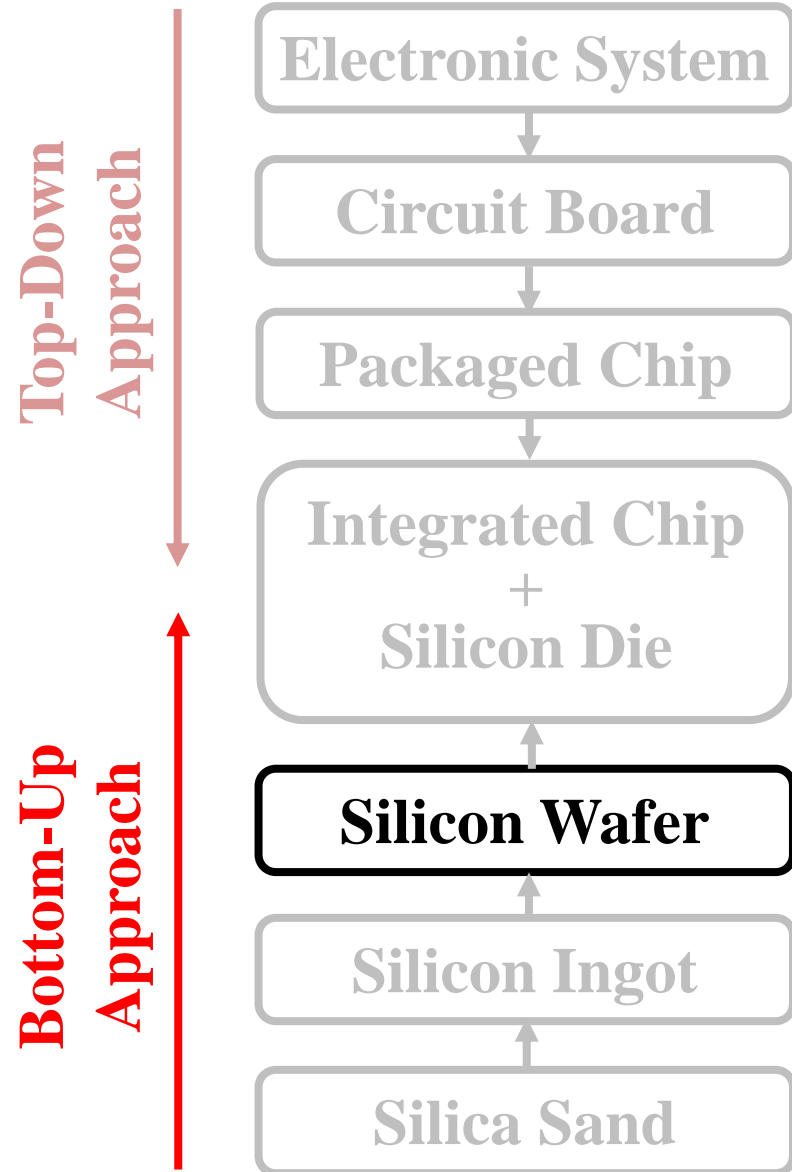
Integrated Chip



Silicon Die



# Silicon Wafer

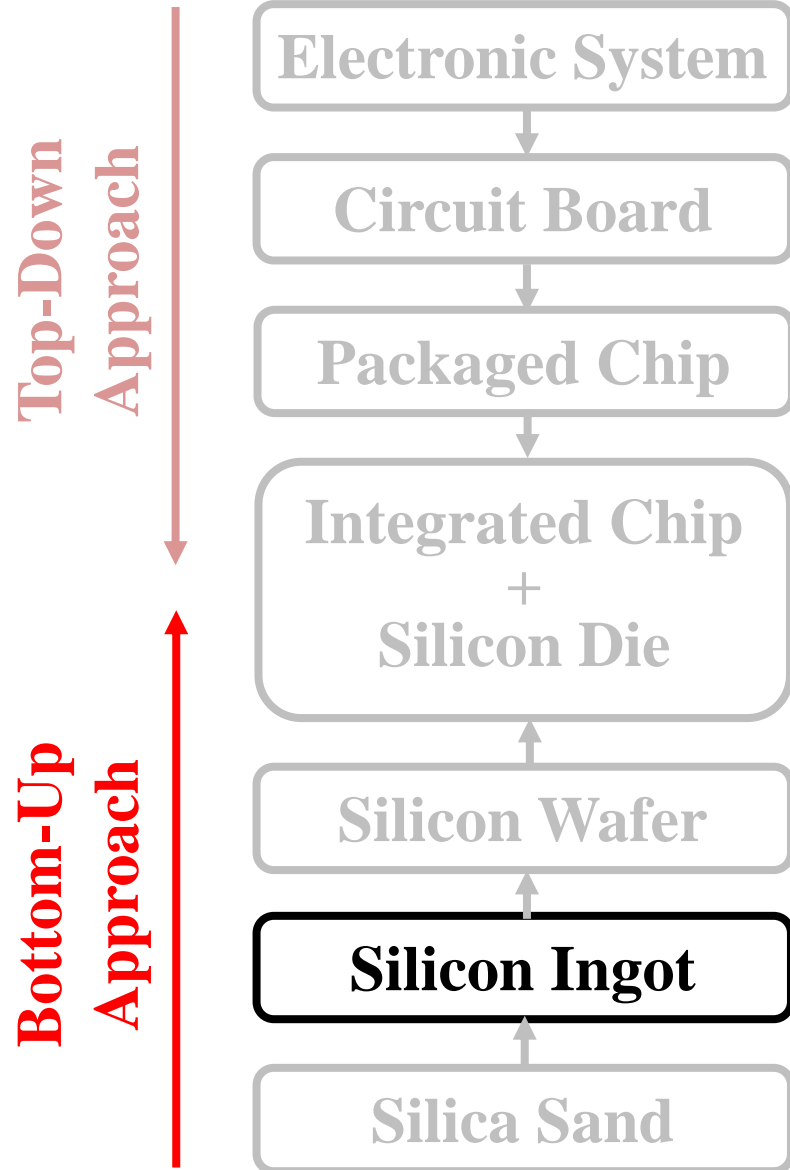


Silicon Wafer



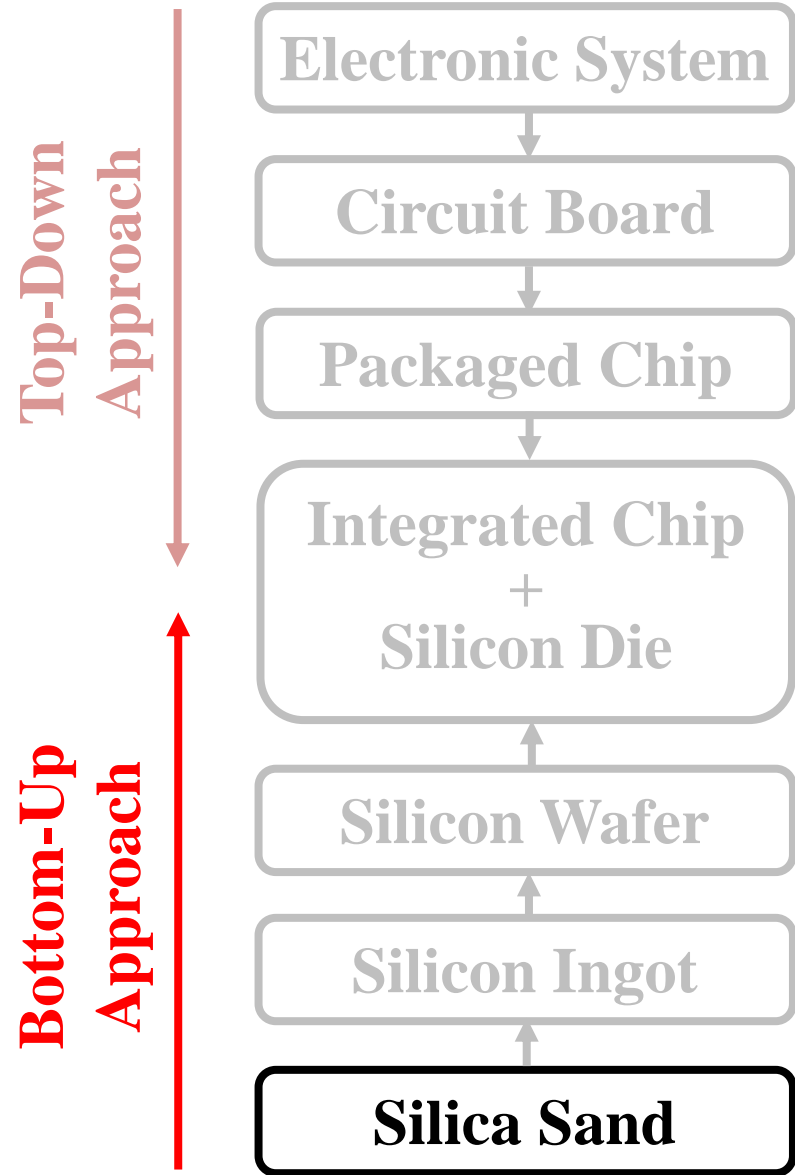
# Silicon Ingot

Silicon ingot





# Silica Sand



Silica Sand



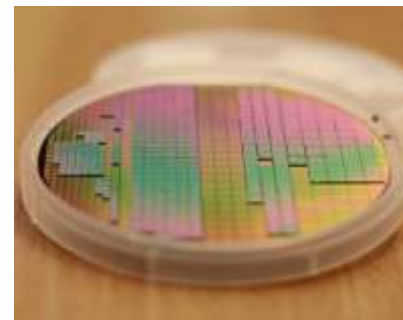
# VLSI Design Summary



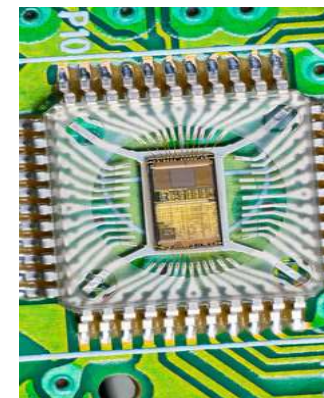
Silica Sand



Silicon Ingot



Silicon Wafer



Integrated Chip



Packaged Chip

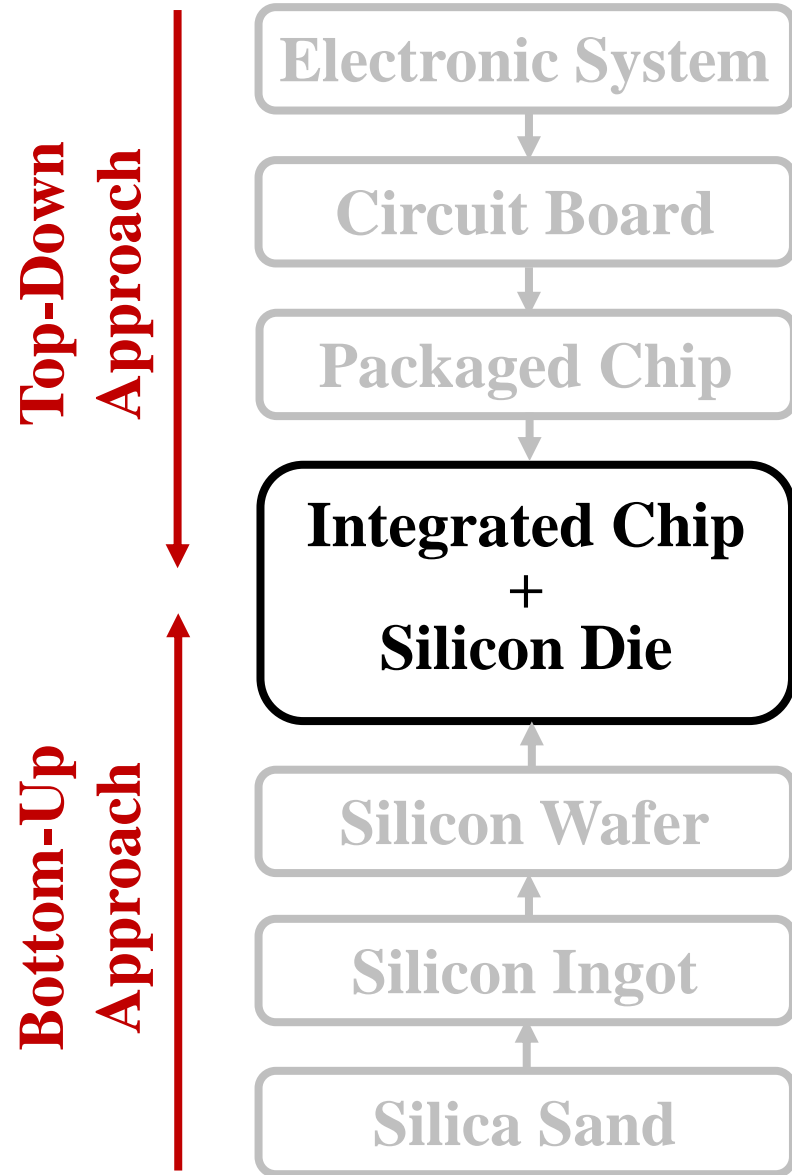


Circuit Board

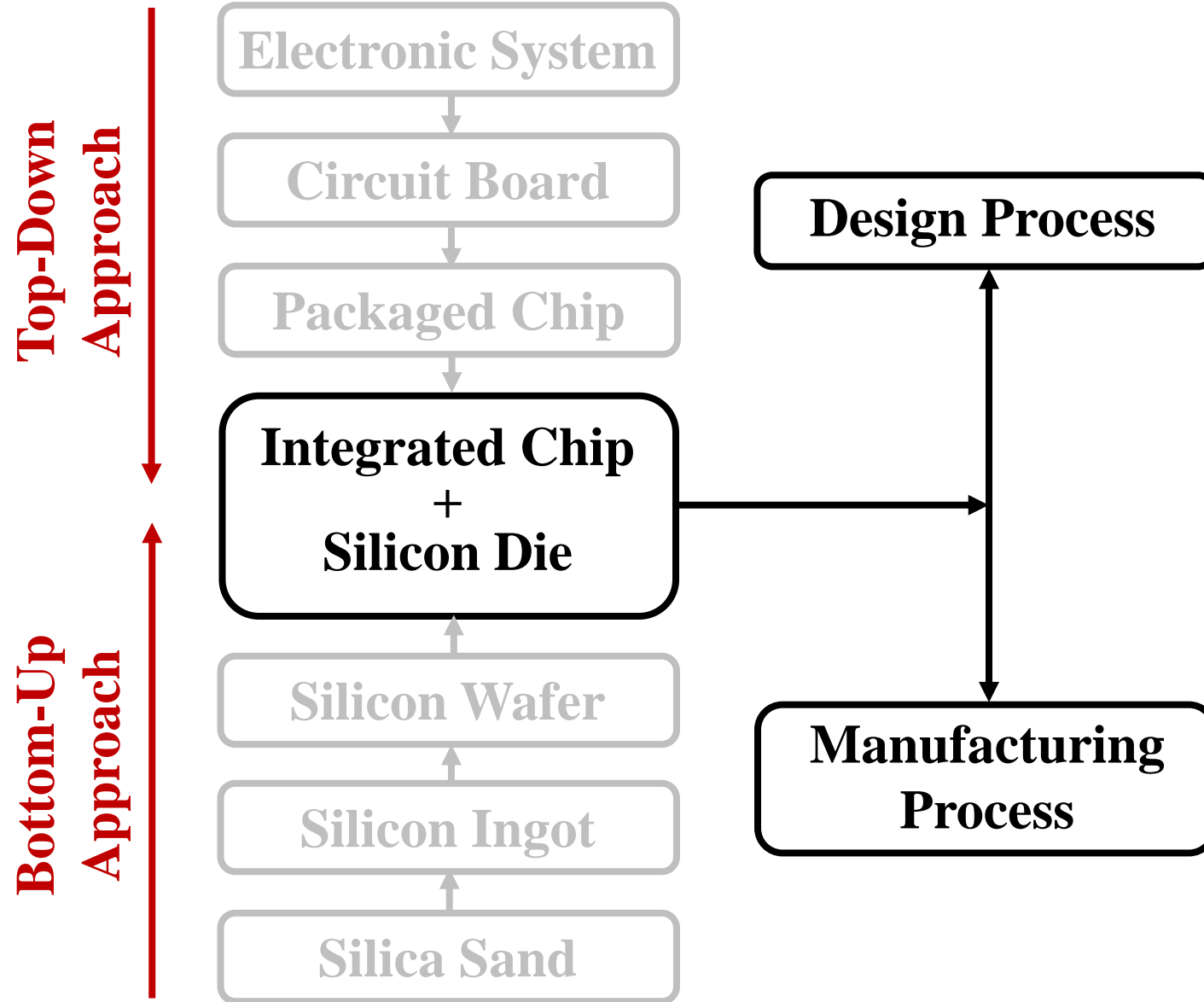


Electronics System

# Outline

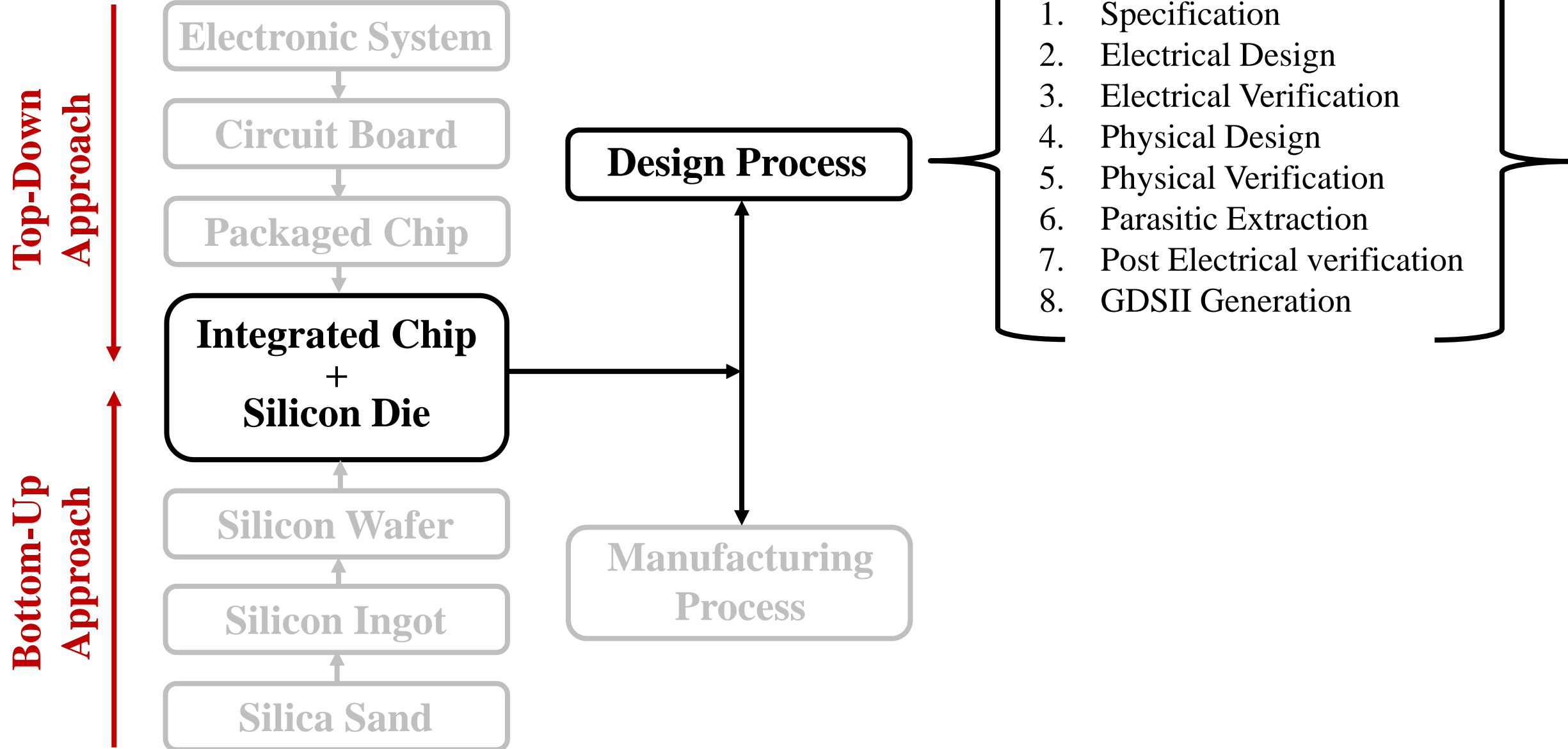


# VLSI Design and Manufacturing Process





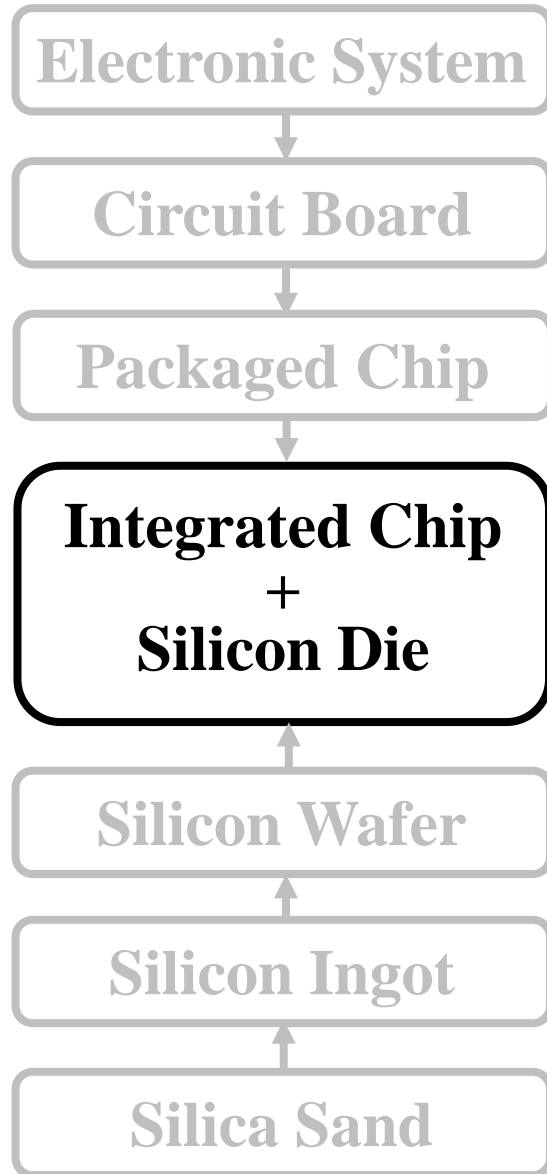
# VLSI Design Process



# VLSI Design Process

**Top-Down  
Approach**

**Bottom-Up  
Approach**



**Design Process**

1. Specification
2. Electrical Design
3. Electrical Verification
4. Physical Design
5. Physical Verification
6. Parasitic Extraction
7. Post Electrical verification
8. GDSII Generation

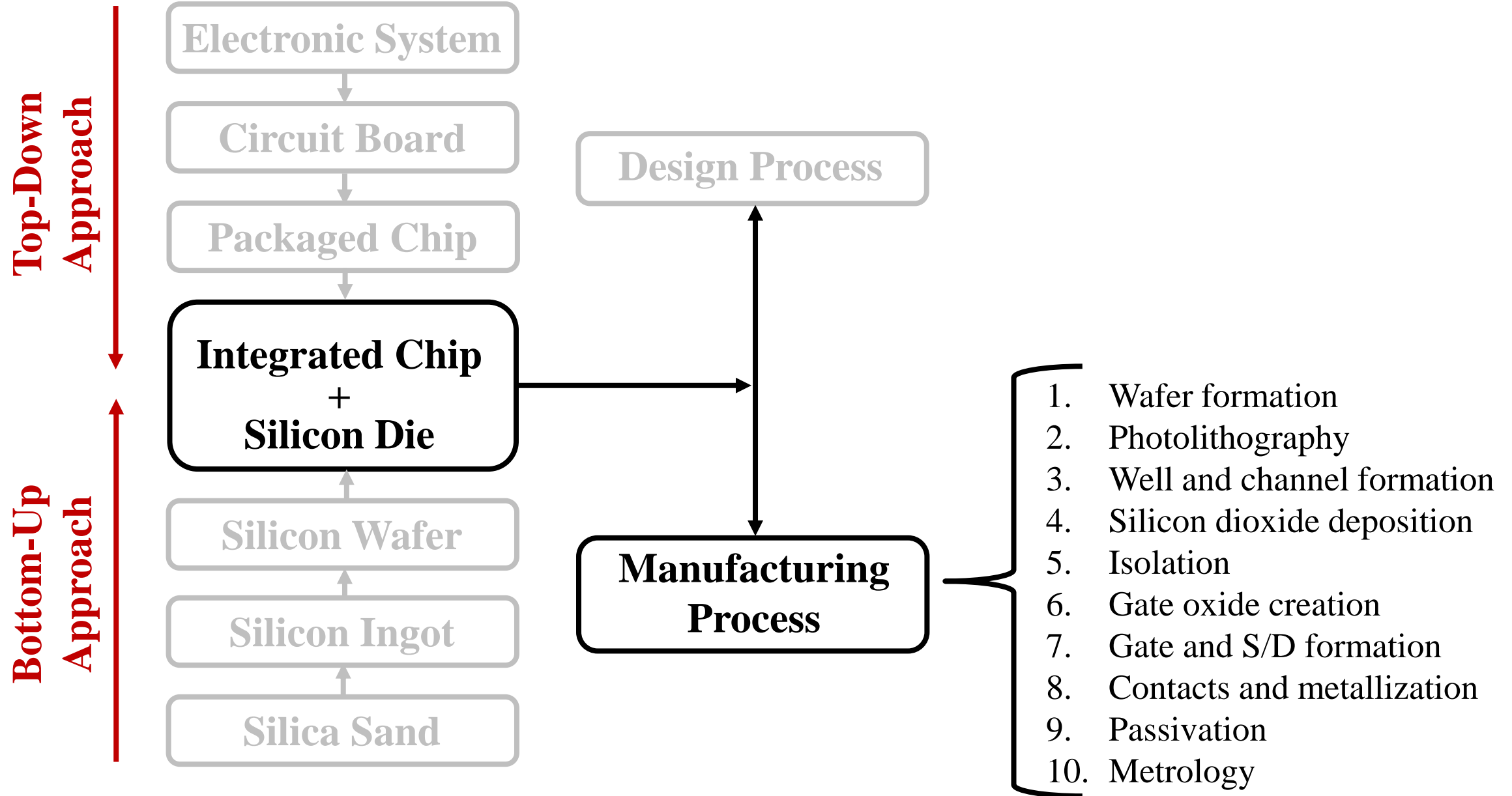
**CAD**

Software or  
tools used in the  
design process

**PDK**

Components or  
devices used in  
design process

# VLSI Manufacturing Process



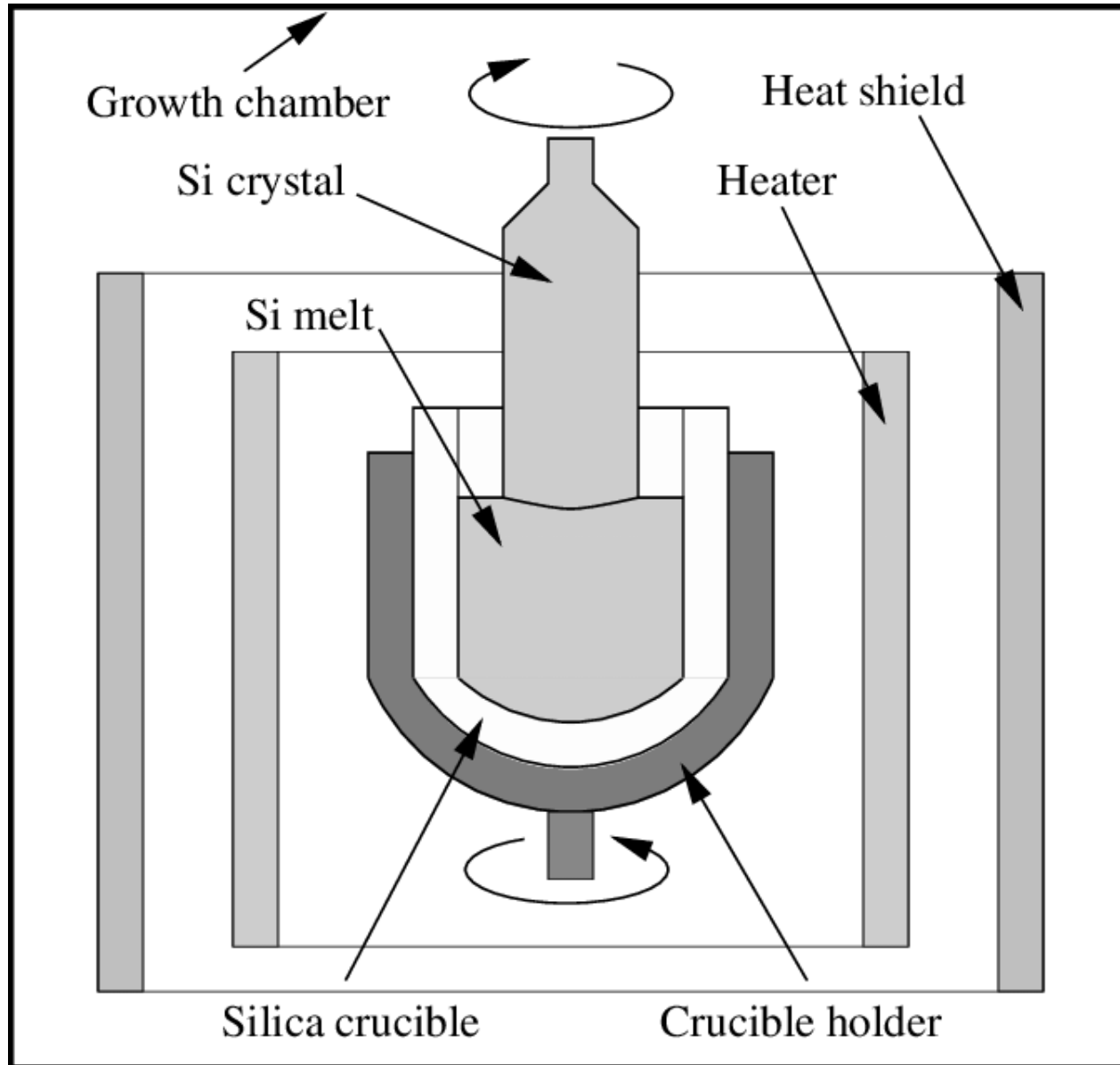
# CMOS Fabrication Process

## Process Steps:

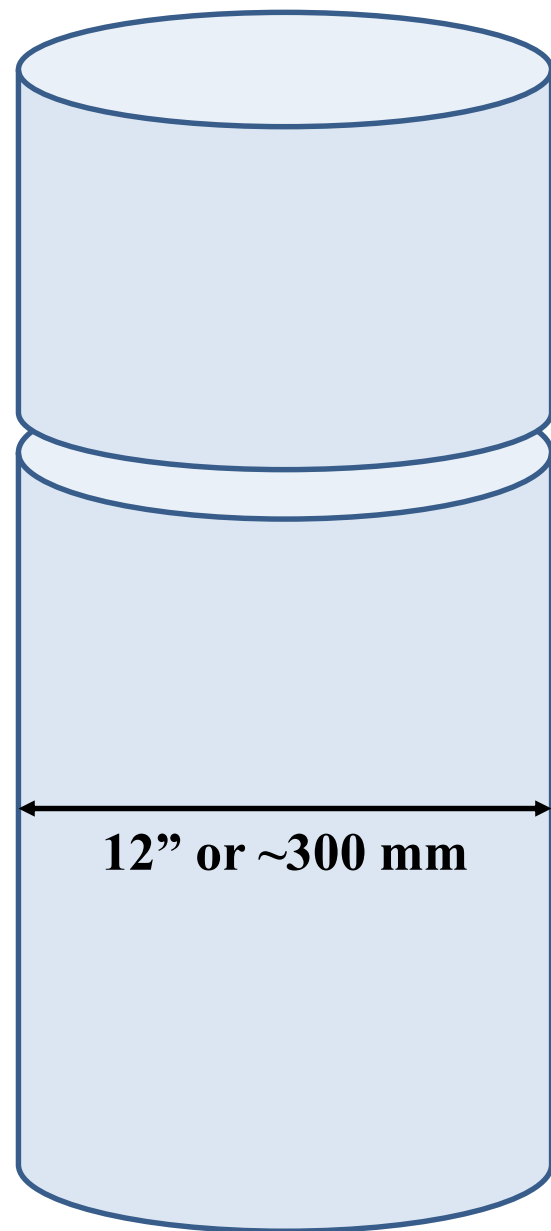
1. Wafer formation (sand-to-silicon)
2. Photolithography
3. Well and Channel Formation
4. Silicon Dioxide (SiO<sub>2</sub>) Deposition
5. Isolation
6. Gate Oxide Creation
7. Gate and Source/Drain Formations
8. Contacts and Metallization
9. Passivation
10. Metrology



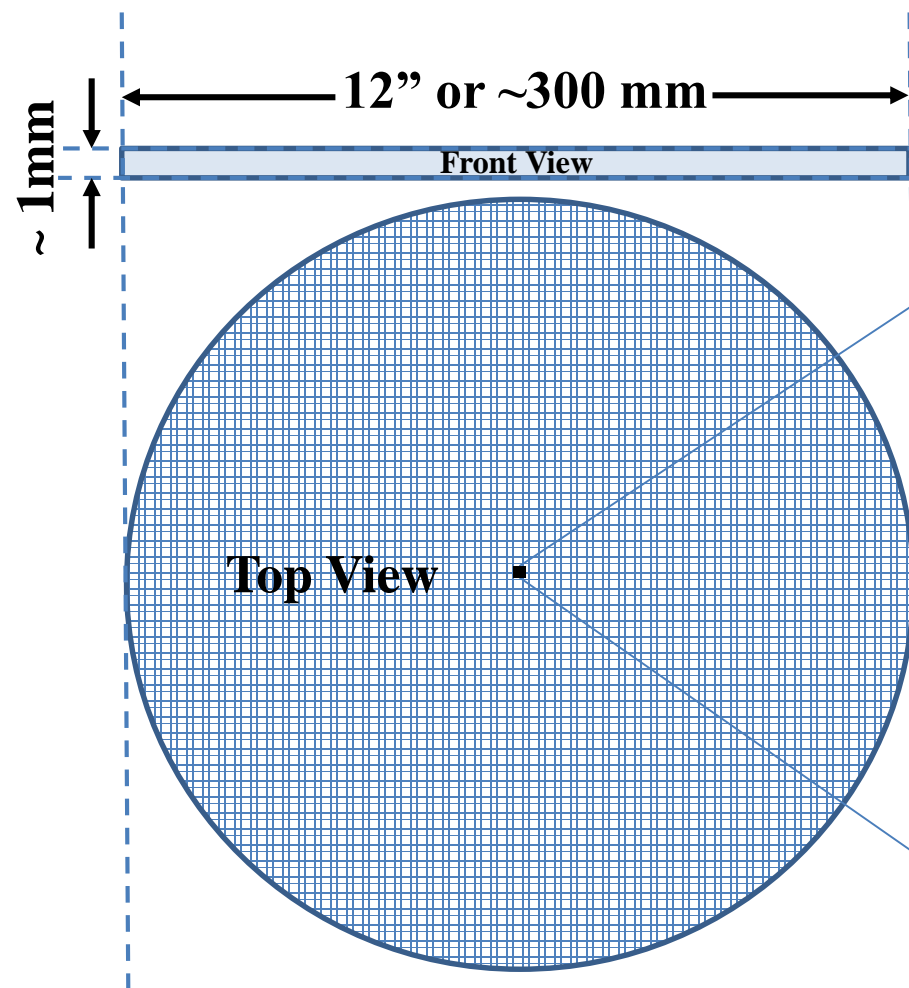
# 1. Wafer Formation (sand-to-silicon)



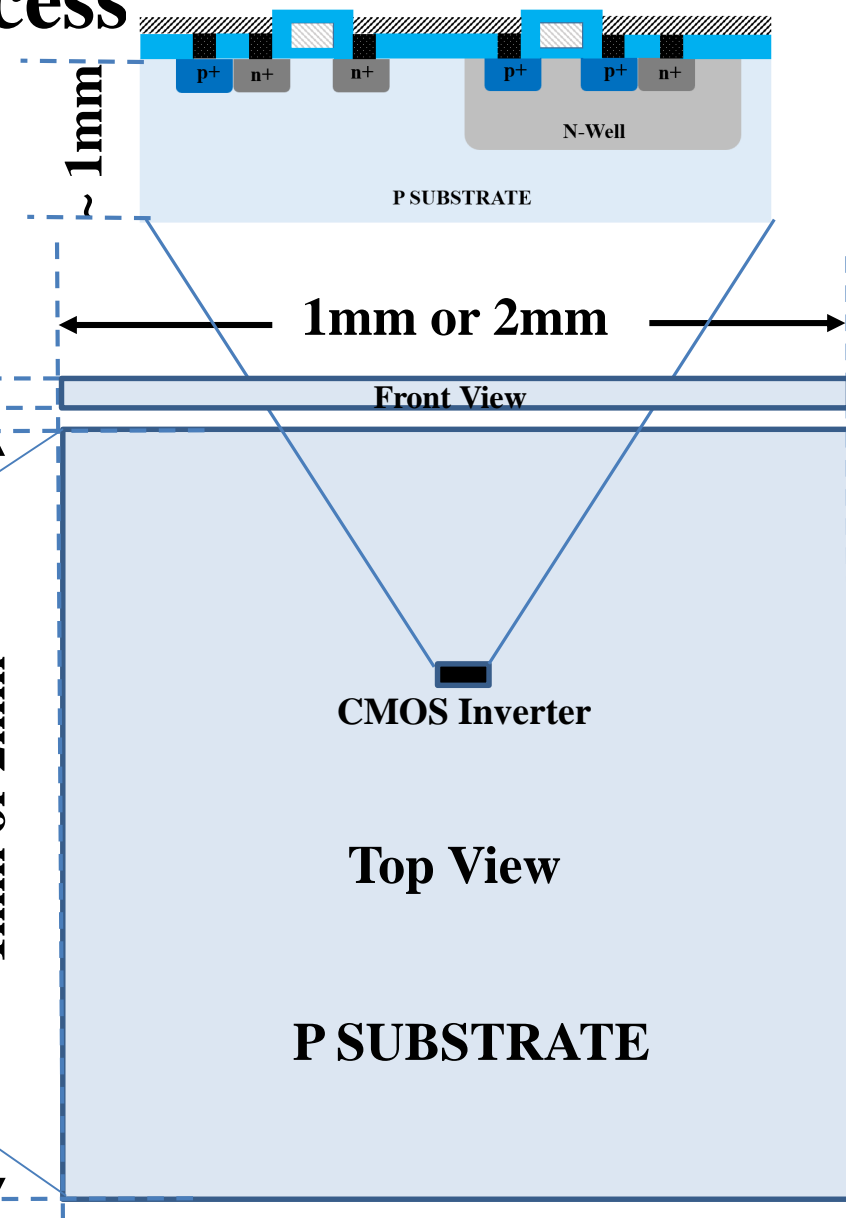
# CMOS Fabrication Process



**SILICON INGOT**

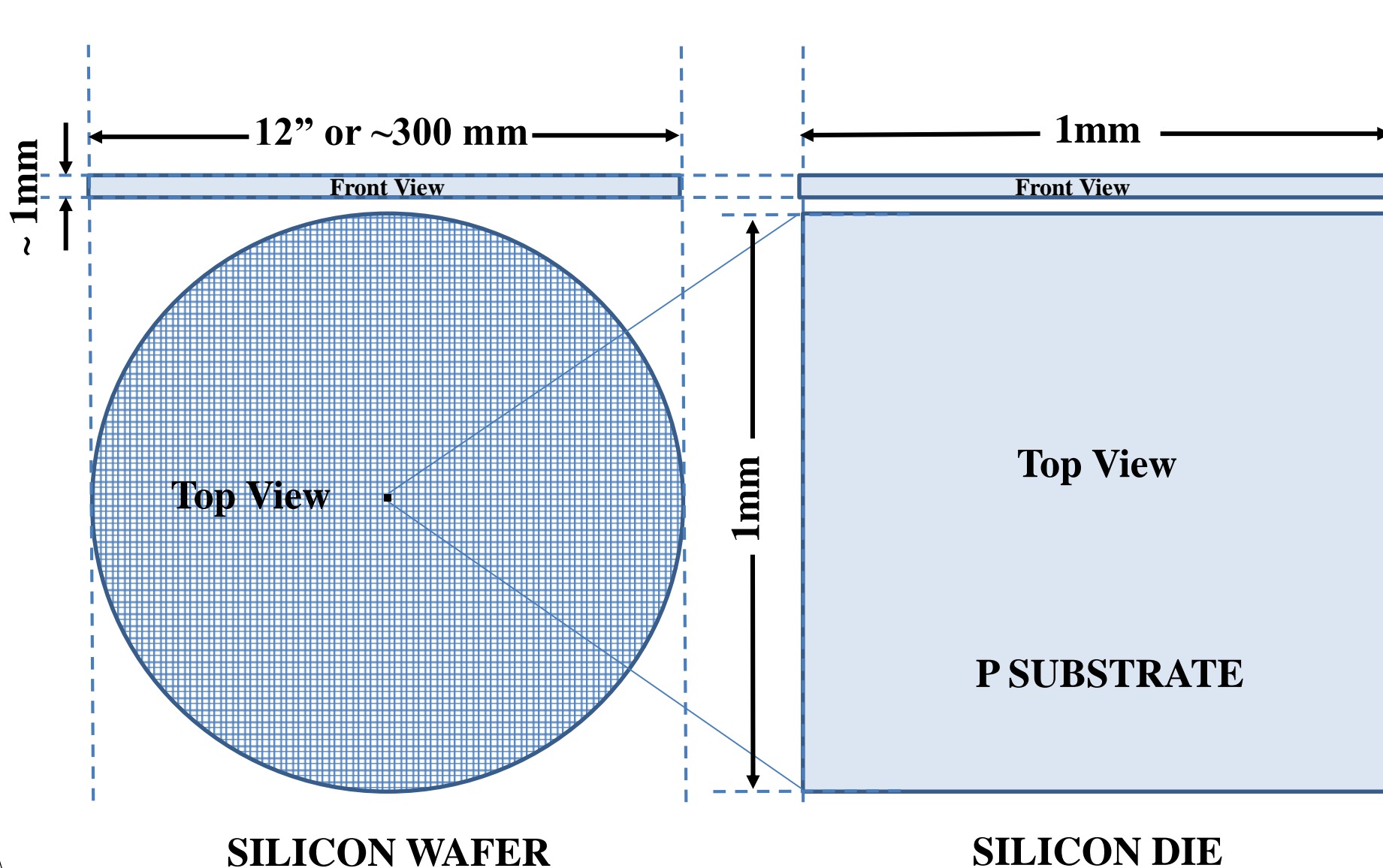


**SILICON WAFER**



**SILICON DIE**

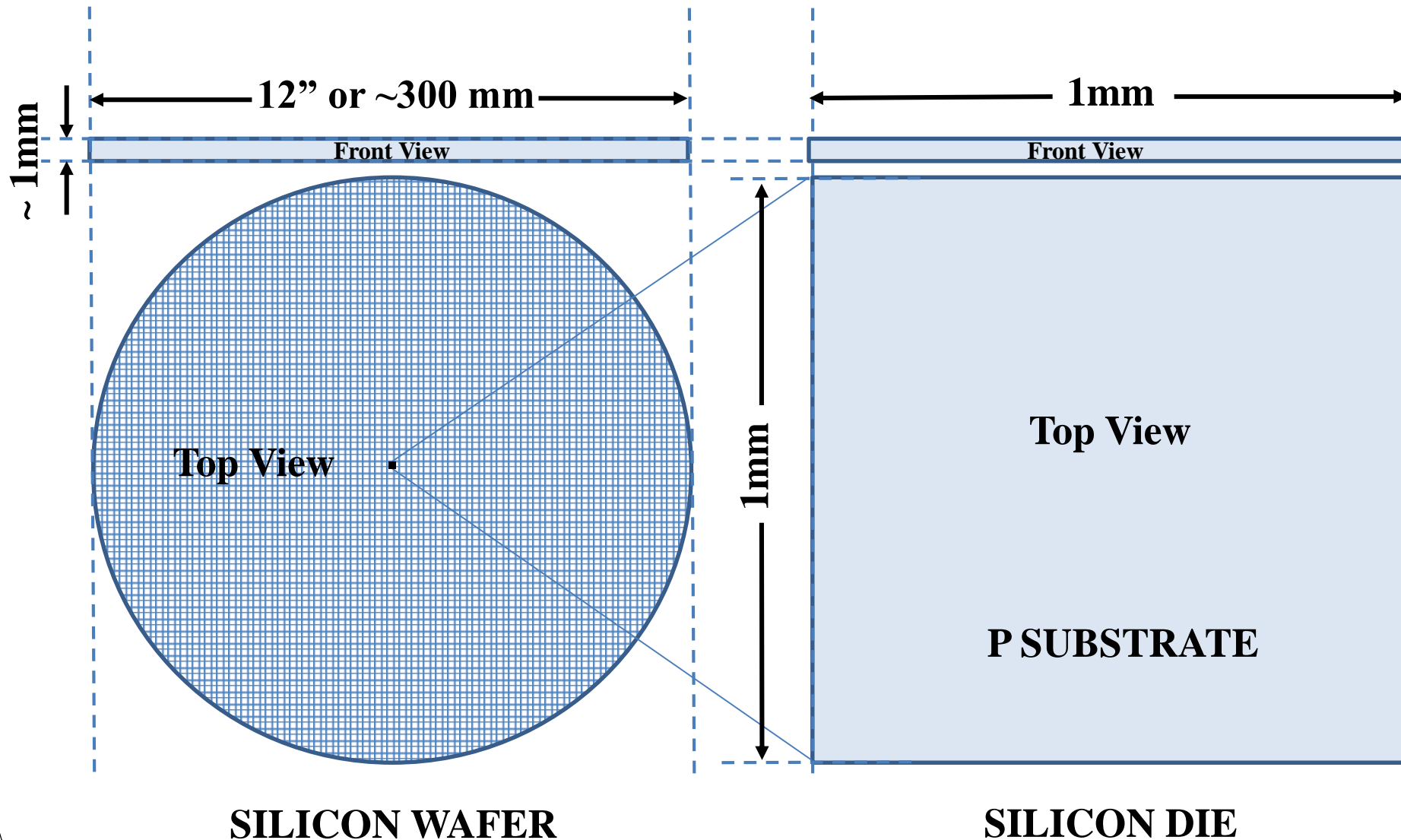
# CMOS Fabrication Process



QUIZ: Refer the left side figure and calculate the number of silicon die can be formed from a single silicon wafer.

- (a) ~300
- (b) ~9,000
- (c) ~70,000
- (d) ~90,000

# CMOS Fabrication Process



**QUIZ:** Refer the left side figure and calculate the number of silicon die can be formed from a single silicon wafer.

- (a) ~300
- (b) ~9,000
- (c) ~70,000
- (d) ~90,000

**Answer:**

Number of die = Area of wafer / Area of die

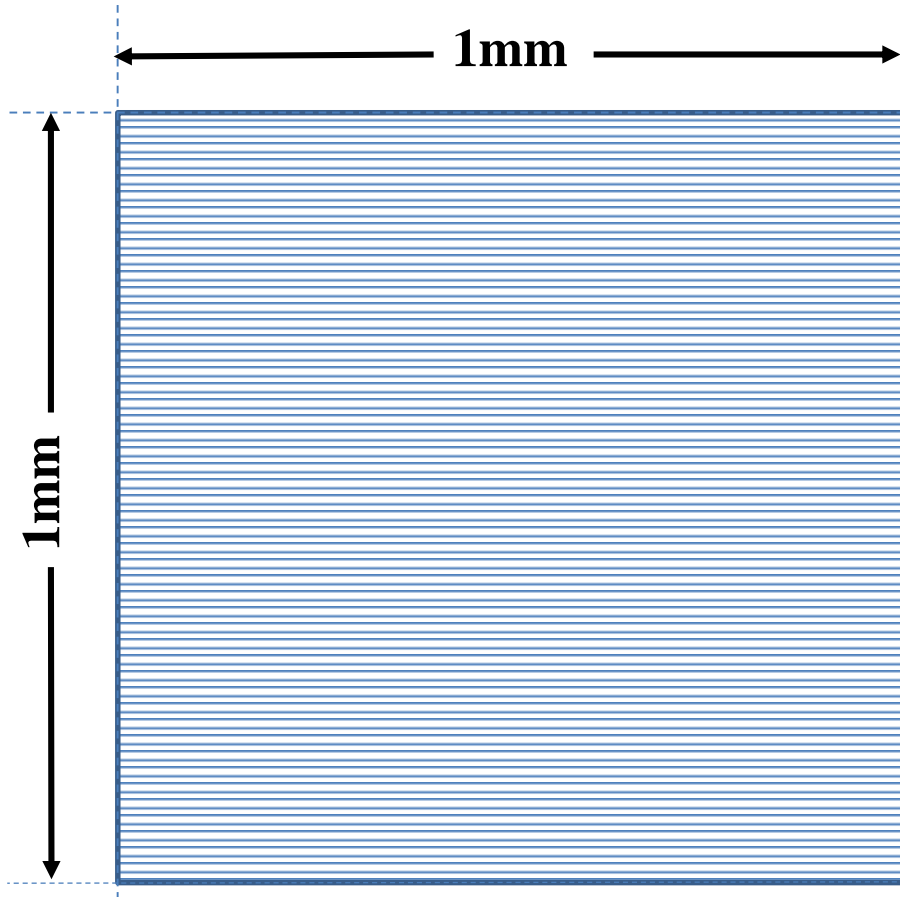
Area of wafer =  $\text{PI} \times 150 \times 150$   
= 70,715 mm<sup>2</sup>

Area of die =  $1 \times 1 = 1 \text{ mm}^2$

No, of die =  $70,715 / 1 = 70,715$



# CMOS Fabrication Process



**SILICON DIE**

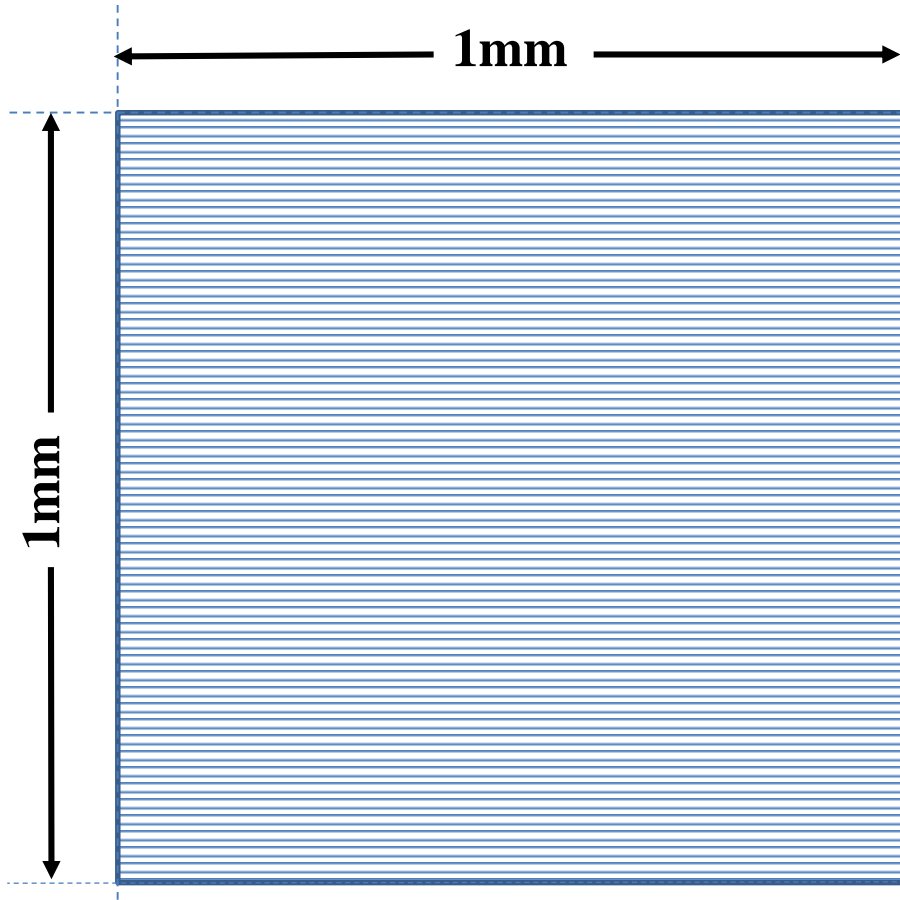
## DATA

- Assume the entire silicon die is a digital chip have all the area filled by only standard cells.
- Assume that in one silicon die there are 1000 equal rows and each having  $1\mu\text{m}$  high.
- Assume that a standard cell having a height of  $1\mu\text{m}$  and a width of  $0.25\mu\text{m}$ .
- Assume standard cell has only one P-MOSFET and one N-MOSFET.
- Assume all the interconnection between all the standard cells are through top metals only.

**QUIZ:** Refer the left side figure and data given, calculate the number of MOS transistors can be put in a single 1mm X 1mm silicon die.

- (a) 1 million
- (b) 2 million
- (c) 4 million
- (d) 8 million

# CMOS Fabrication Process



**SILICON DIE**

- Assume the entire silicon die is a digital chip have all the area filled by only standard cells.
- Assume that in one silicon die there are 1000 equal rows and each having  $1\mu\text{m}$  height.
- Assume that a standard cell having a height of  $1\mu\text{m}$  and a width of  $0.25\mu\text{m}$ .
- Assume standard cell has only one P-MOSFET and one N-MOSFET.
- Assume all the interconnection between all the standard cells are through top metals only.

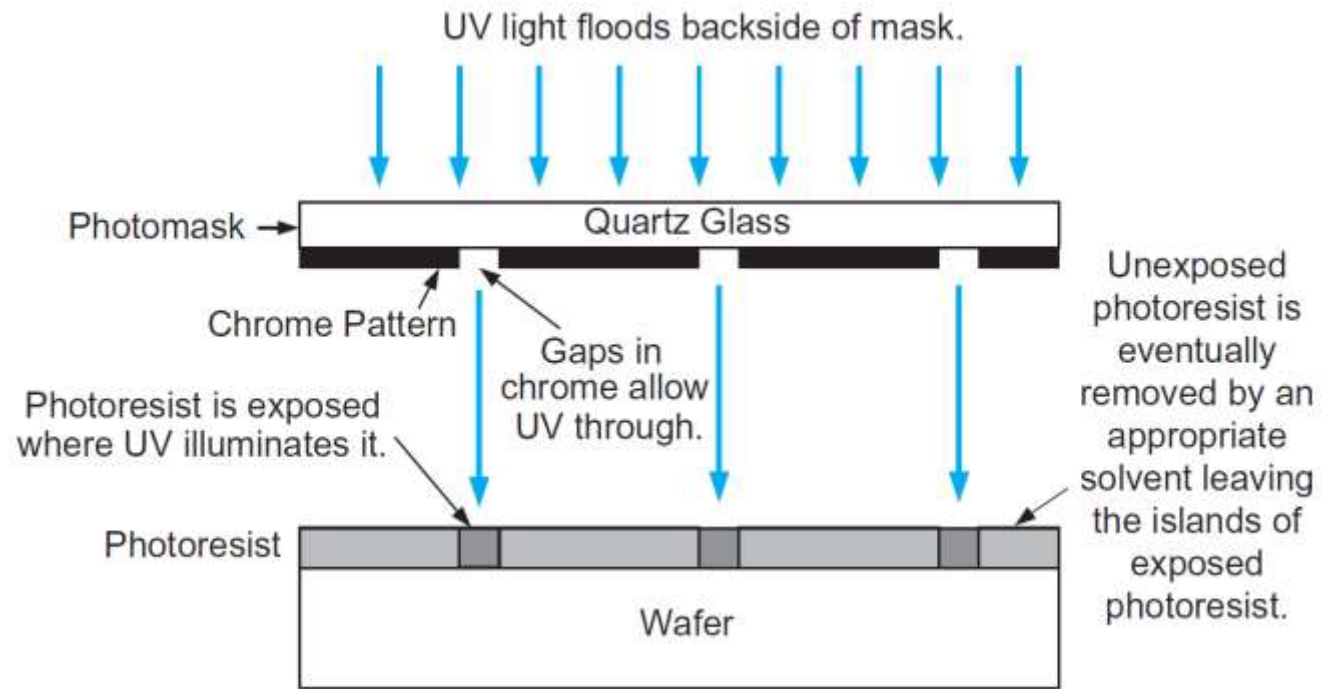
**QUIZ:** Refer the left side figure and data given, calculate the number of MOS transistors can be put in a single  $1\text{mm} \times 1\text{mm}$  silicon die.

- (a) 1 million
- (b) 2 million
- (c) 4 million
- (d) 8 million

**Answer:**

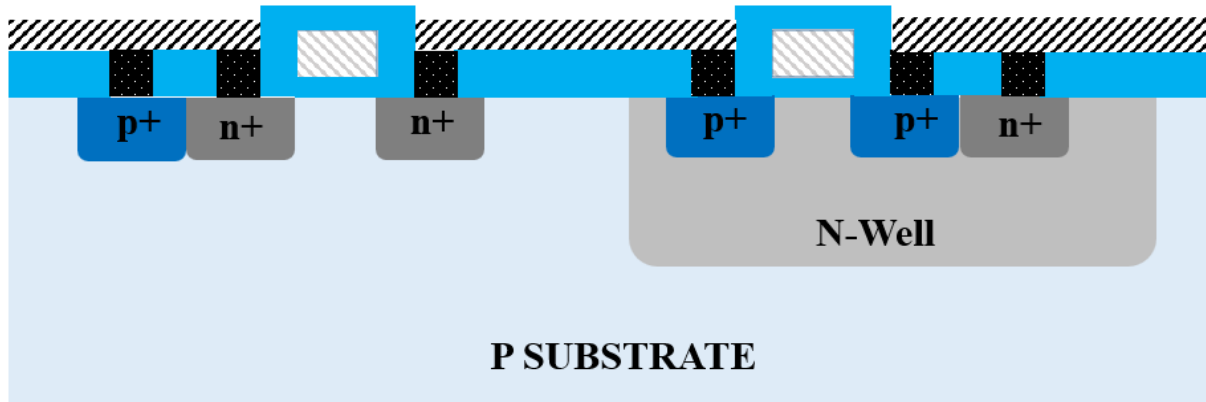
- There are 1000 rows and each having  $1\mu\text{m}$  height.
- Per row 4000 standard cells
- Per row 8000 transistors
- In 1000 rows,  
 $8000 \times 1000 = 8000000$
- Or 8 million transistors

## 2. Photolithography

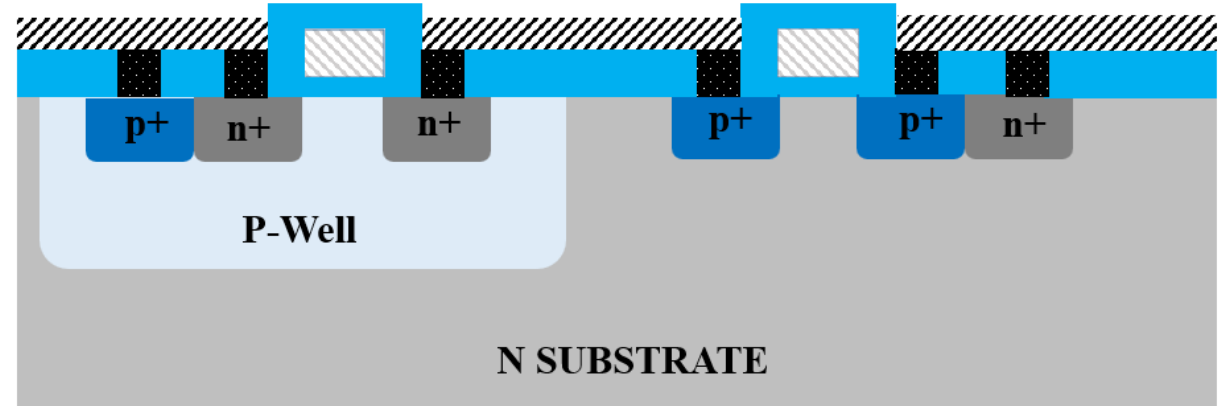


Photolithography process [Waste and Harris]

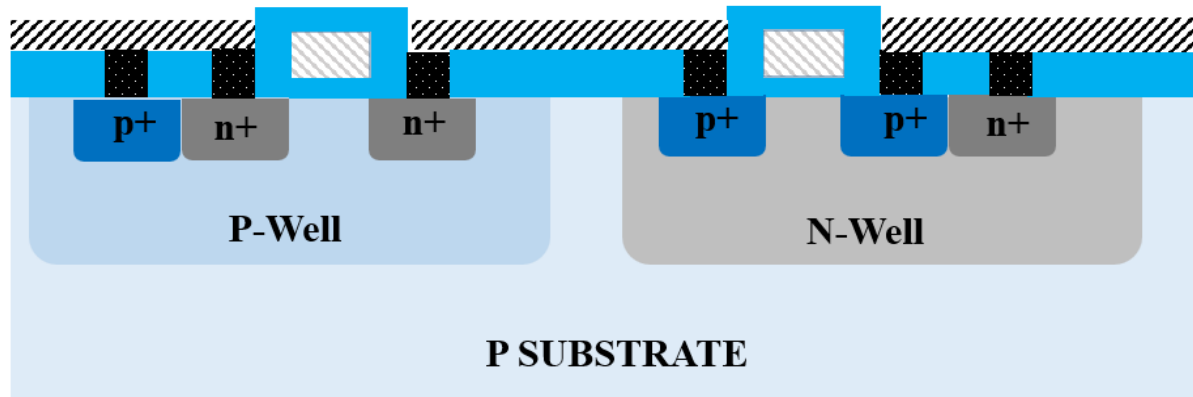
### 3. Well and Channel Formation



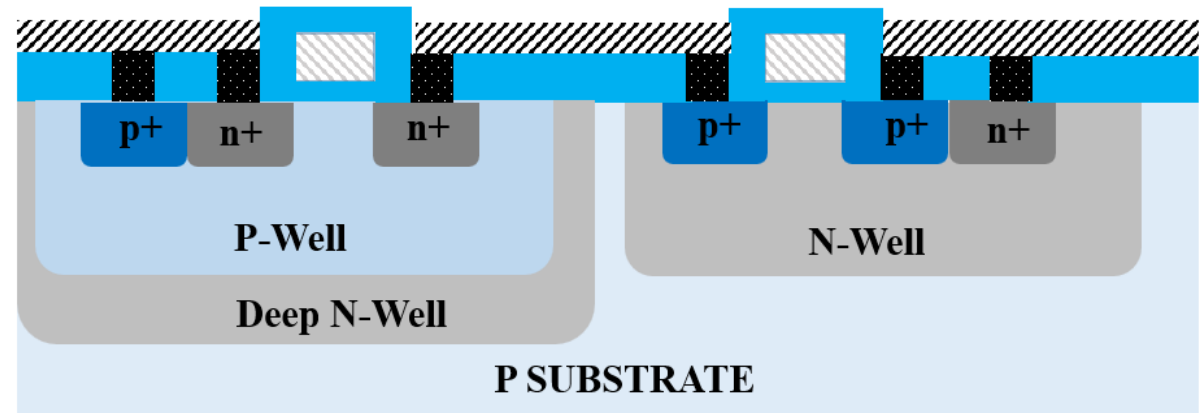
1. N-Well Process



2. P-Well Process



3. Twin-Well Process

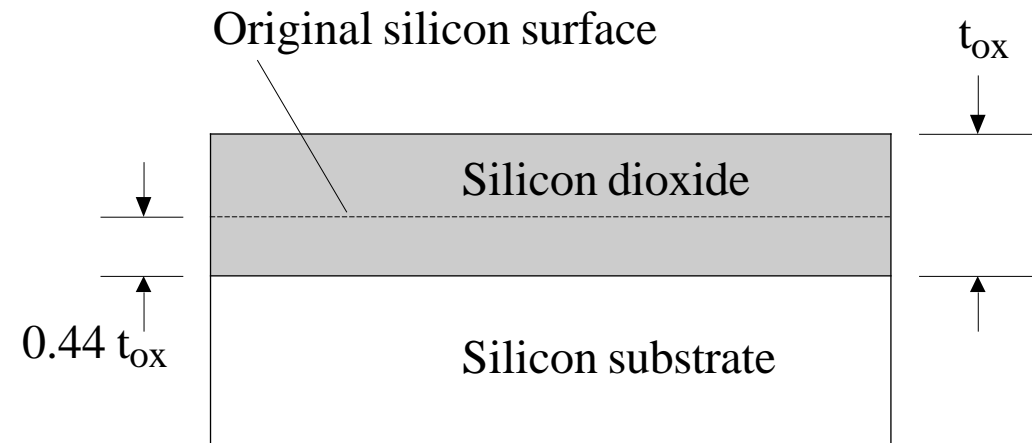


4. Tripple-Well Process



## 4. Silicon Dioxide (SiO<sub>2</sub>)

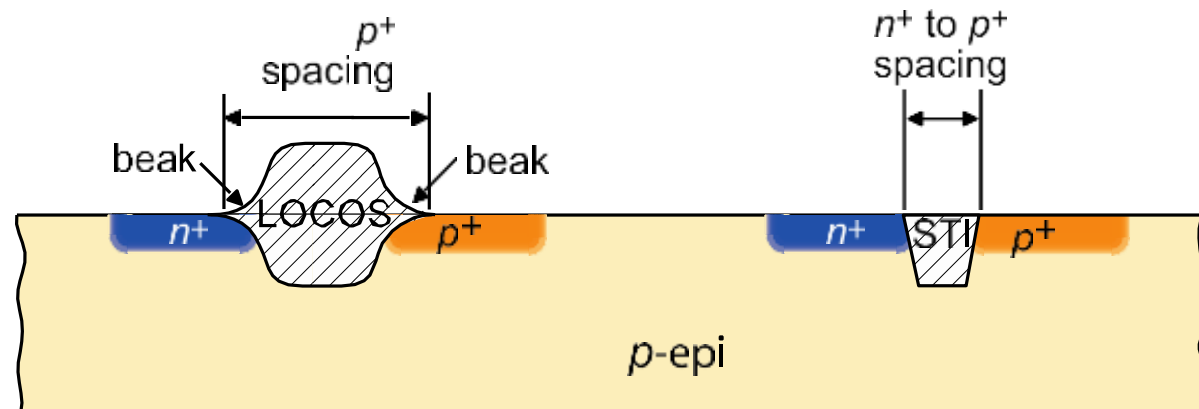
- Oxidation of silicon is achieved by heating silicon wafers in an oxidizing atmosphere. The following are some common approaches:
- **Wet Oxidation:** The oxidizing atmosphere contains water vapor.
  - The temperature is usually between 900 °C and 1000 °C.
  - Wet oxidation is a rapid process.
  - Used to form thick field oxides
- **Dry Oxidation:** The oxidizing atmosphere is pure oxygen.
  - Temperatures are in the region of 1200 °C to achieve an acceptable growth rate.
  - Dry oxidation forms a better-quality oxide than wet oxidation.
  - Used to form thin, highly controlled gate oxides.



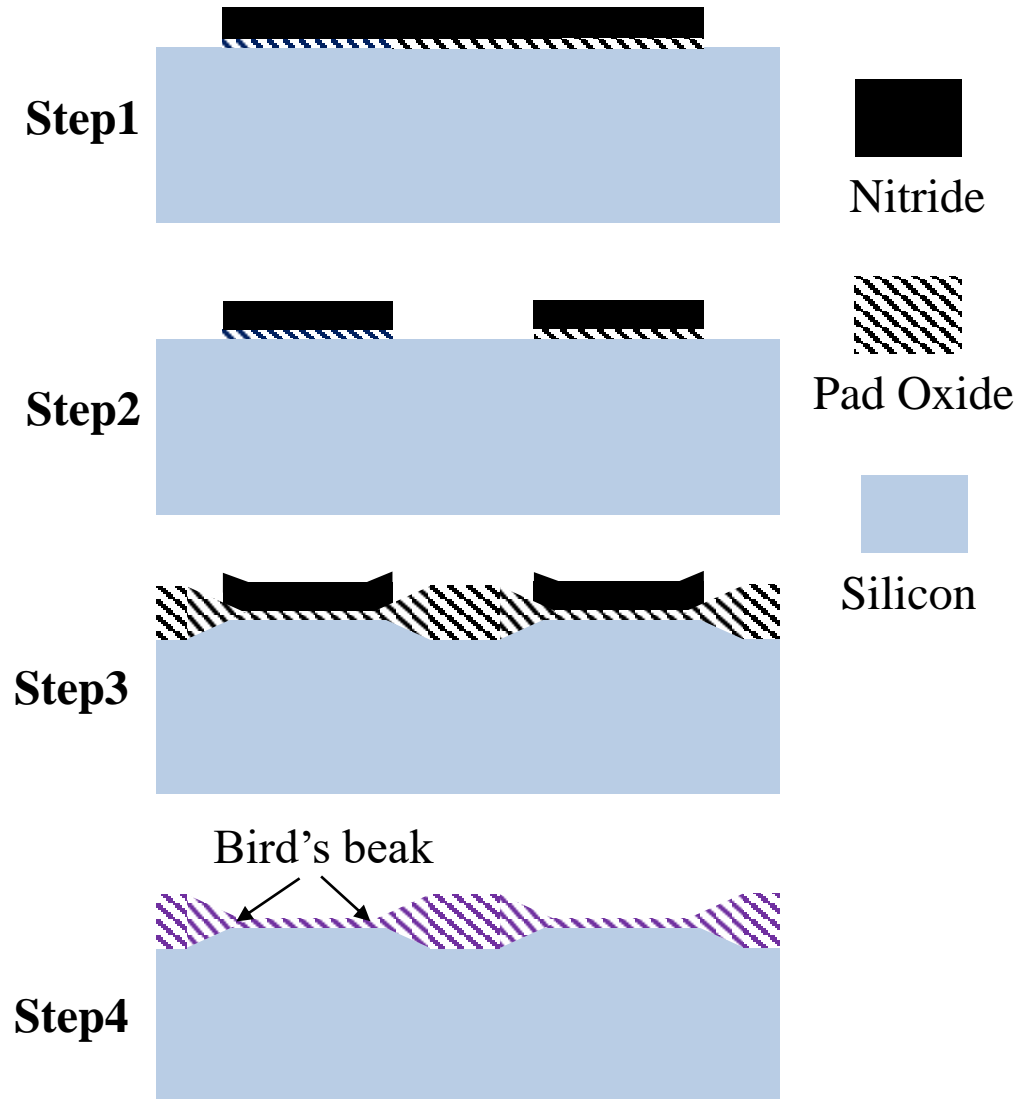
# 5. Isolation

## 5. Isolation

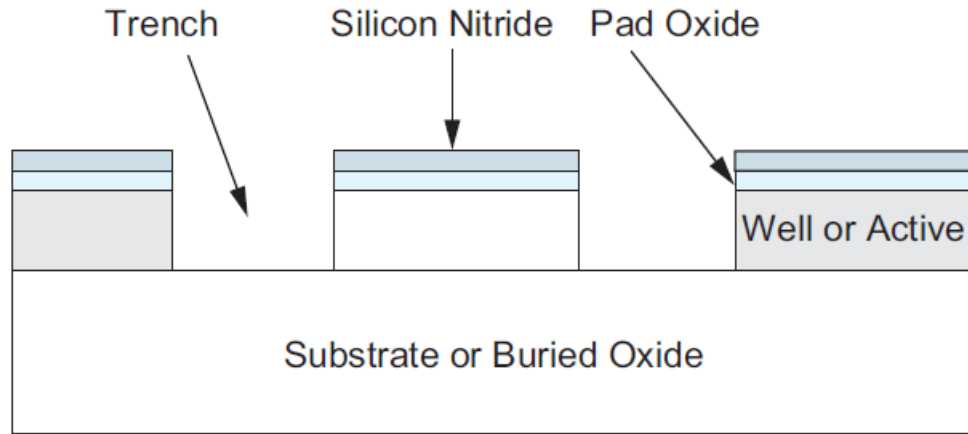
- Individual devices in a CMOS process need to be isolated from one another
- The transistor gate consists of a thin gate oxide layer.
- The thick oxide used to be formed by a process called Local Oxidation of Silicon (LOCOS).
- A problem with LOCOS-based processes is the transition between thick and thin oxide, which extends some distance laterally to form a so-called bird's beak.
- Starting around the 0.35  $\mu\text{m}$  node, STI was introduced to avoid the problems with LOCOS.
- STI forms insulating trenches of  $\text{SiO}_2$  surrounding the transistors (everywhere except the active area).



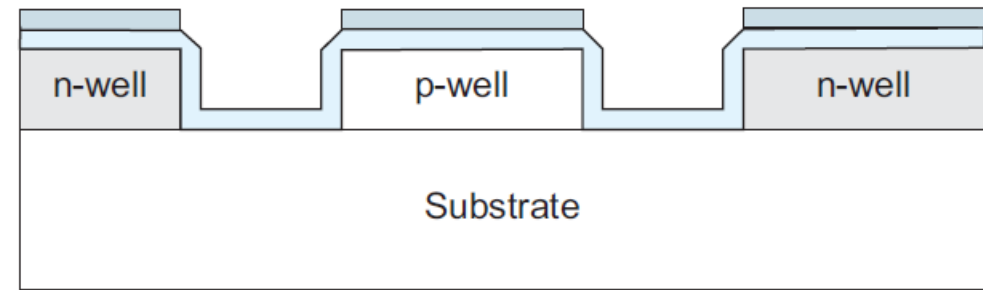
# Local Oxidation of Silicon (LOCOS)



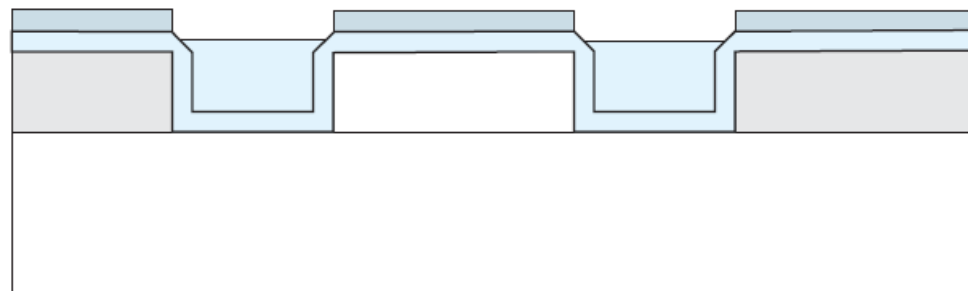
# Sallow Trench Isolation



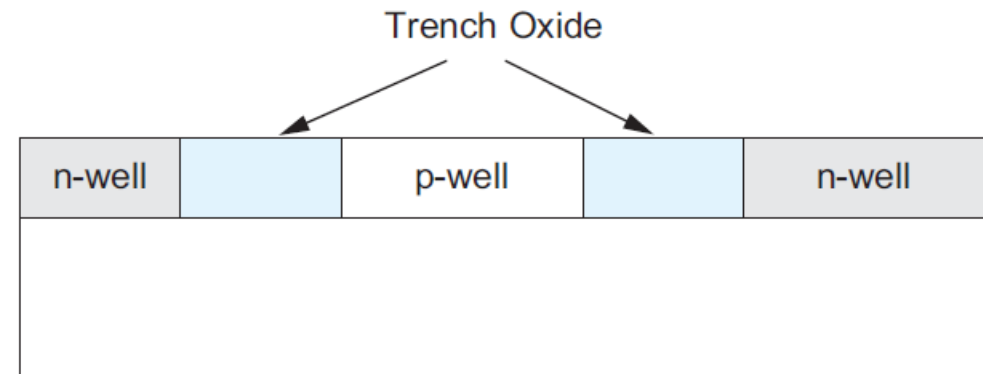
(a) Trench Etch



(b) Liner Oxidation



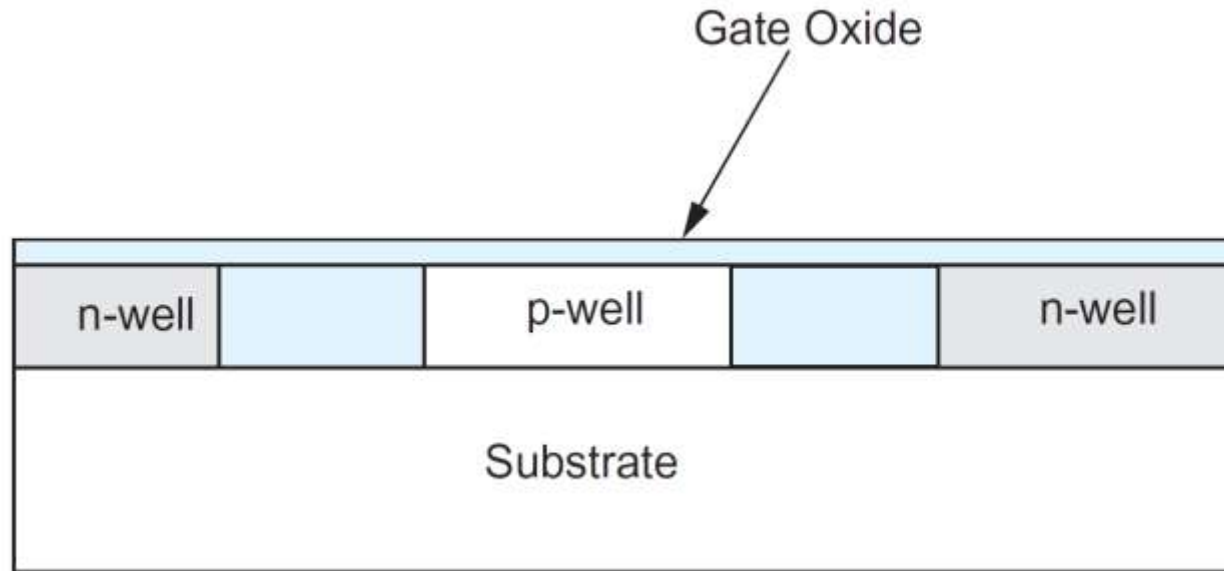
(c) Fill Trench with Dielectric



(d) CMP for Planarization

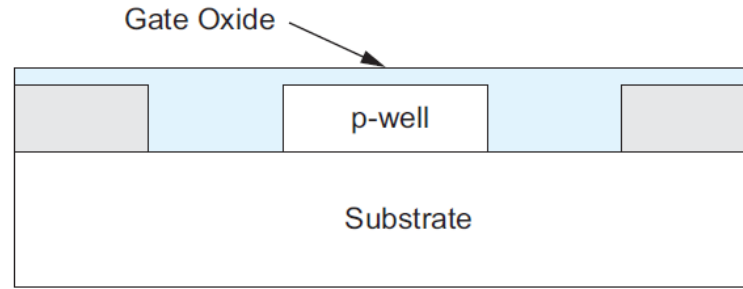
## 6. Gate Oxide

- The next step in the process is to form the gate oxide for the transistors. As mentioned, this is most commonly in the form of silicon dioxide ( $\text{SiO}_2$ ). The transistor gate consists of a thin gate oxide layer.

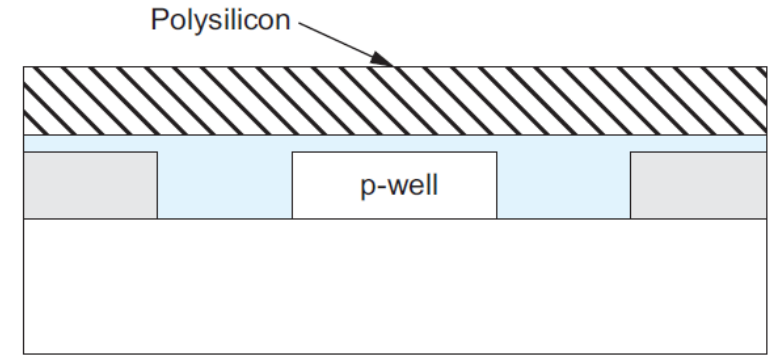


## 7. Gate and Source/Drain Formation

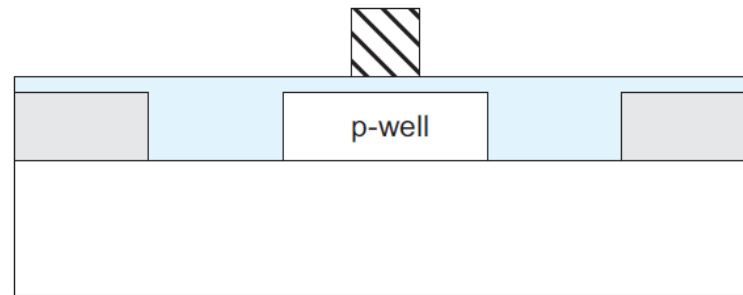
- a) Grow gate oxide
- b) Deposit polysilicon
- c) Pattern polysilicon
- d) Etch exposed gate oxide
- e) Implant PMOS and NMOS



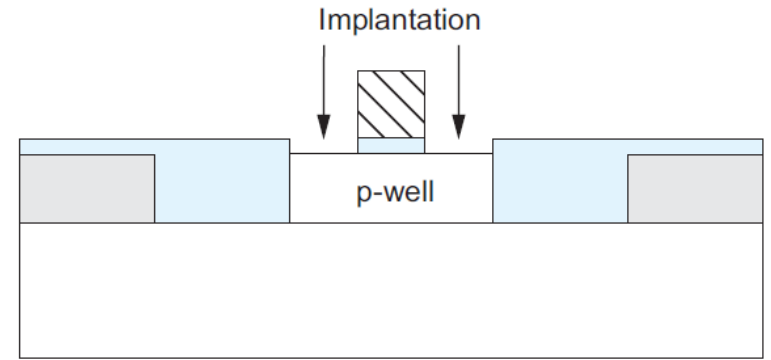
(a)



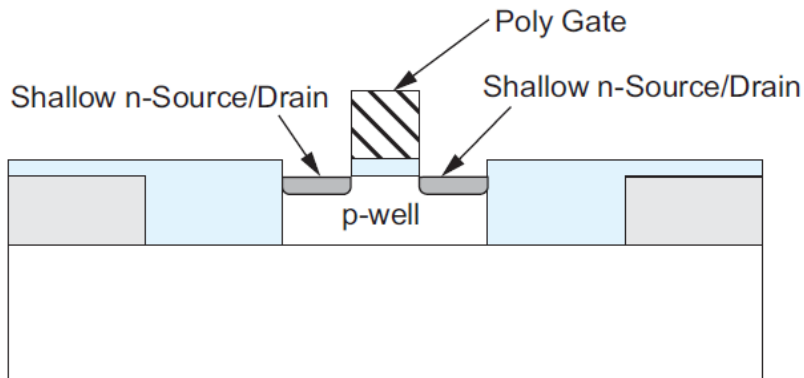
(b)



(c)



(d)

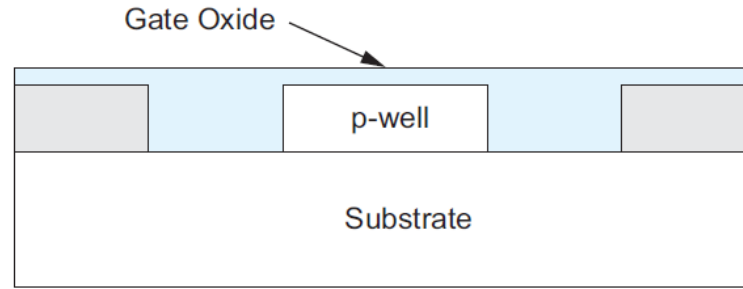


(e)

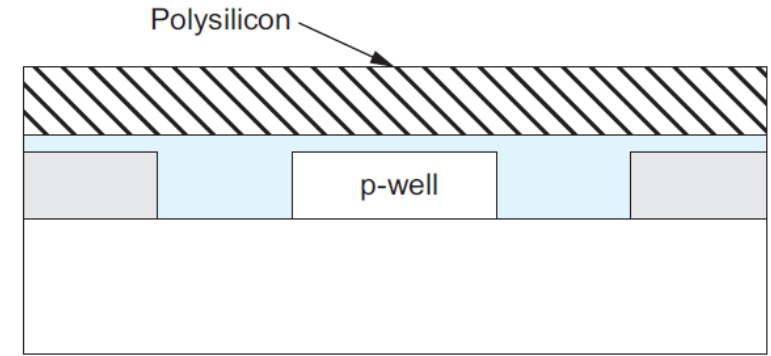
## 7. Gate and Source/Drain Formation

- a) Grow gate oxide
- b) Deposit polysilicon
- c) Pattern polysilicon
- d) Etch exposed gate oxide
- e) Implant PMOS and NMOS

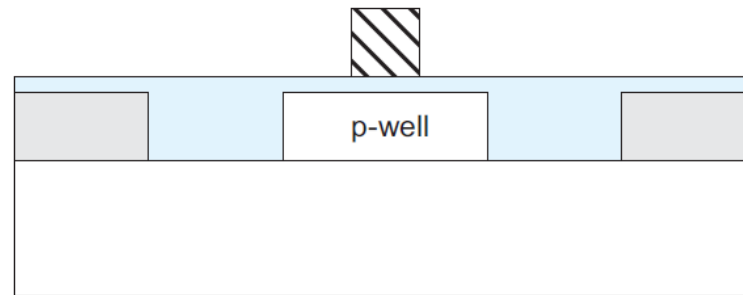
Why not Metal gate?



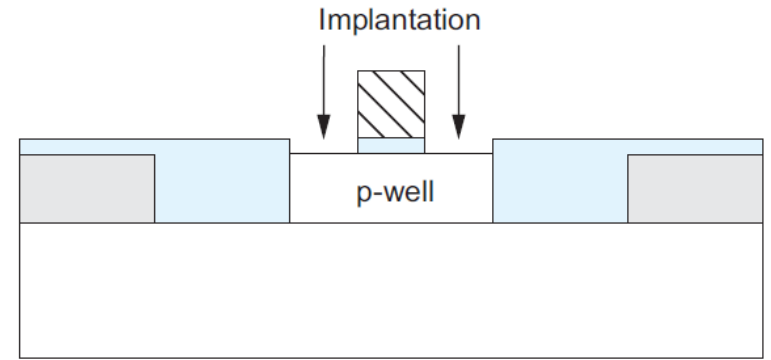
(a)



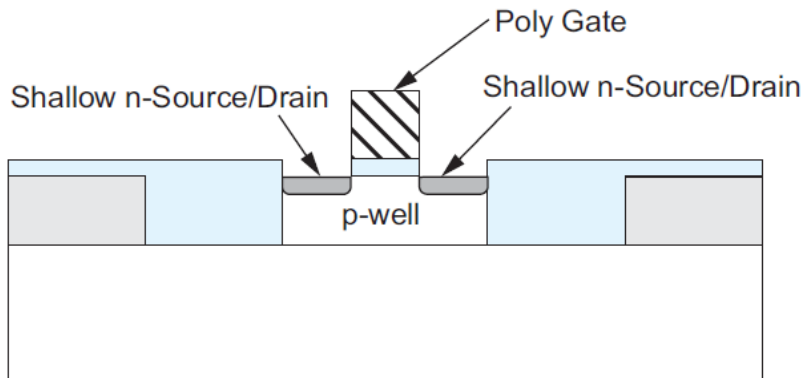
(b)



(c)



(d)

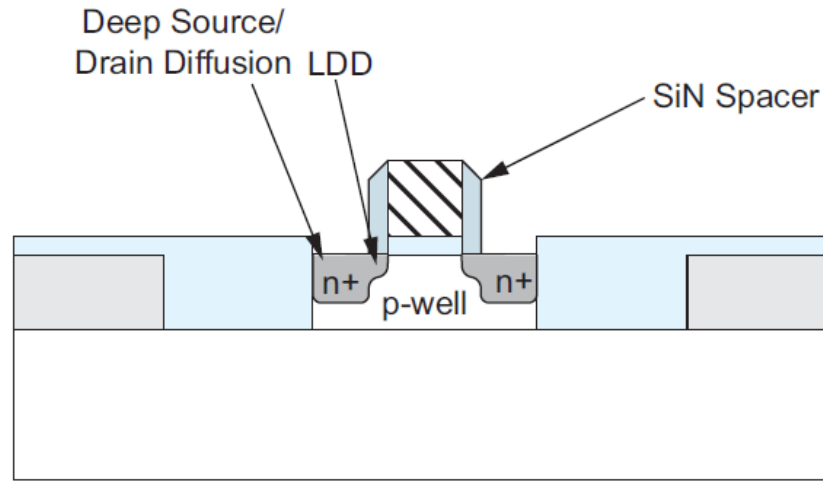


(e)

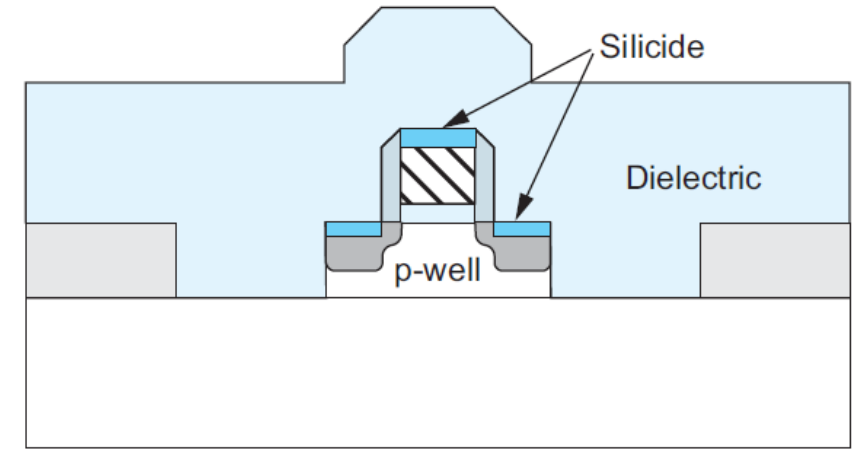


## 7. Gate and Source/Drain Formation

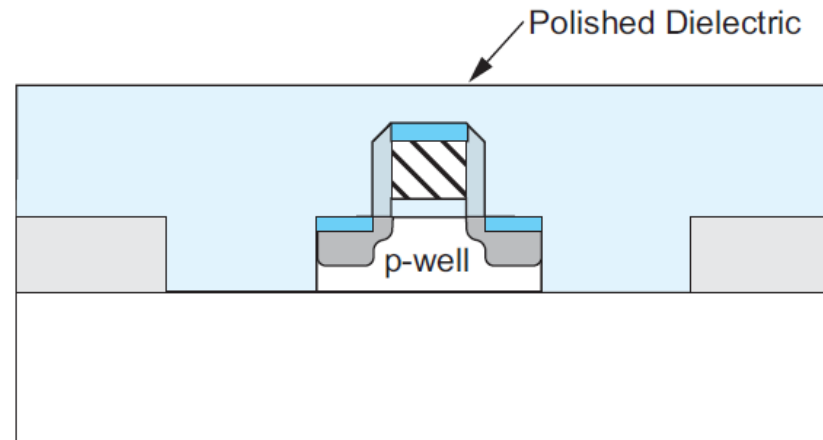
- a) Short-channel engineering
- b) Silicide Gate and Source/Drain
- c) Chemical and Mechanical Polishing



(a)

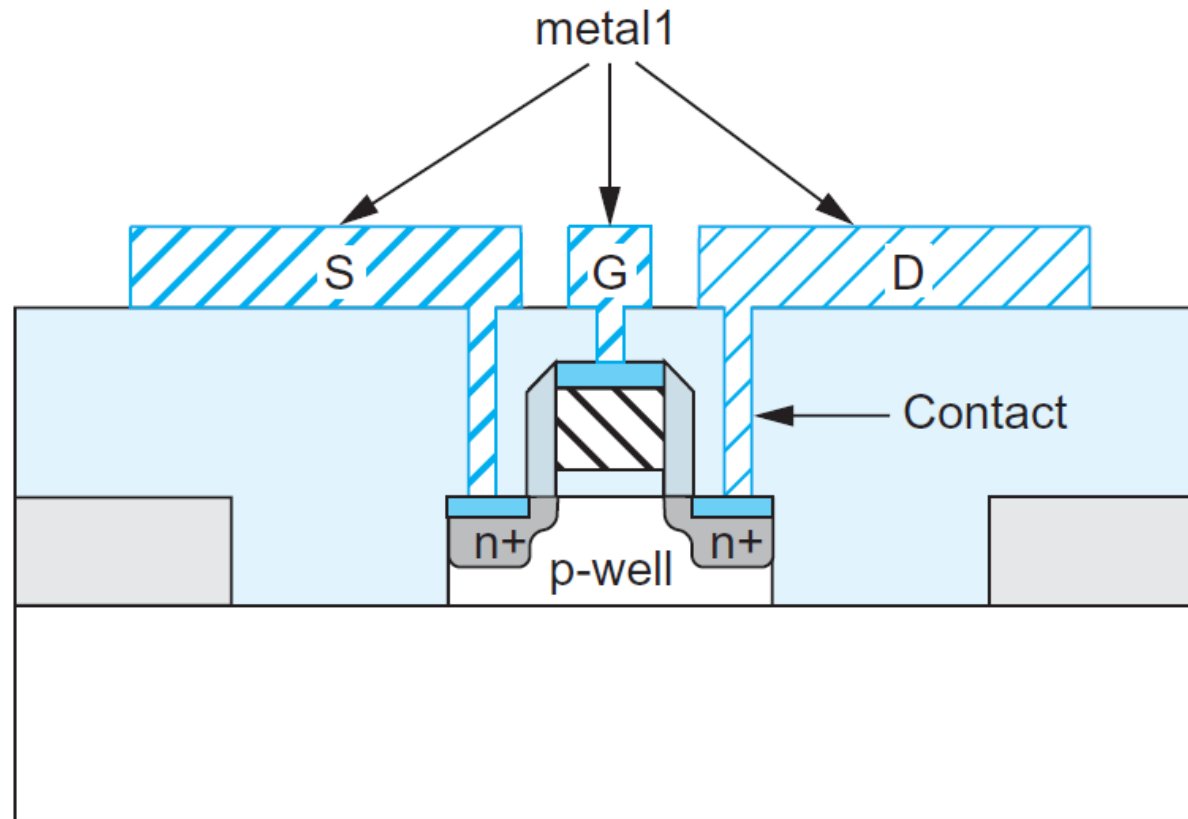


(b)

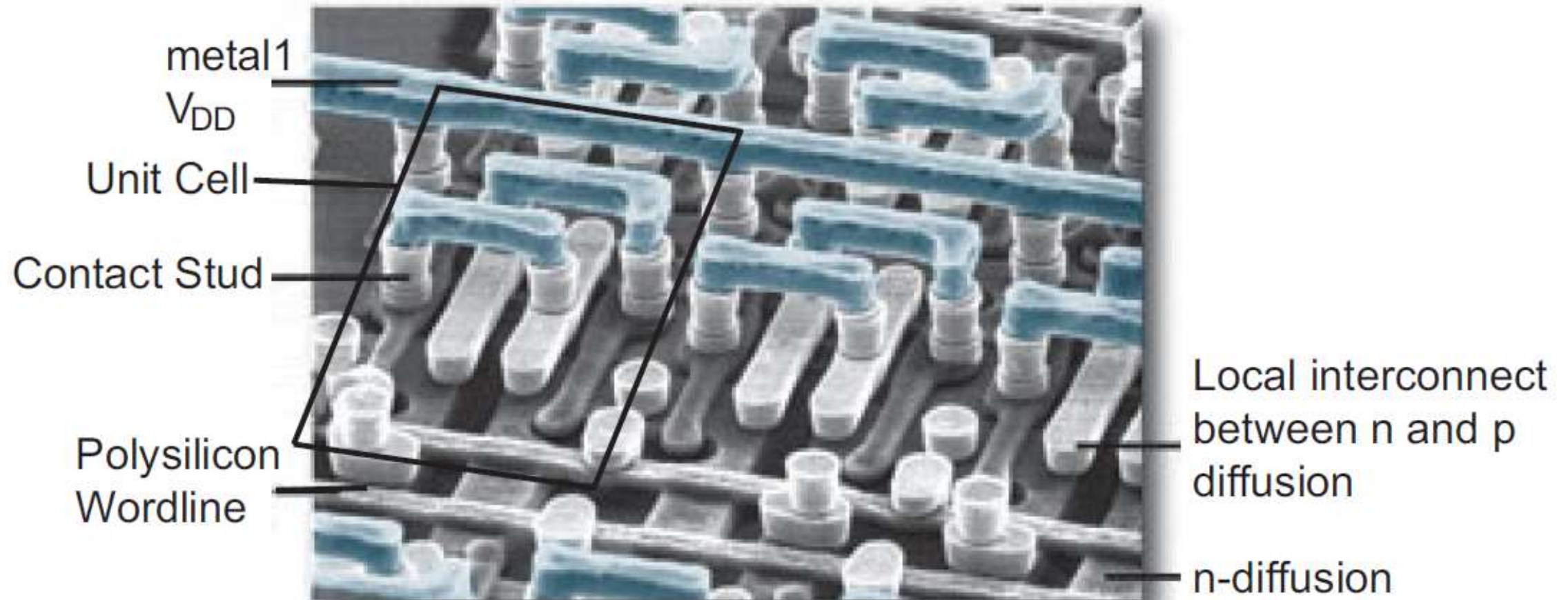


(c)

## 8. Contacts and Metalization



## 8. Contacts and Metallization



Partially completed 6-transistor SRAM array using local interconnect (Courtesy: Waste and Harris)

## **9. Passivation**

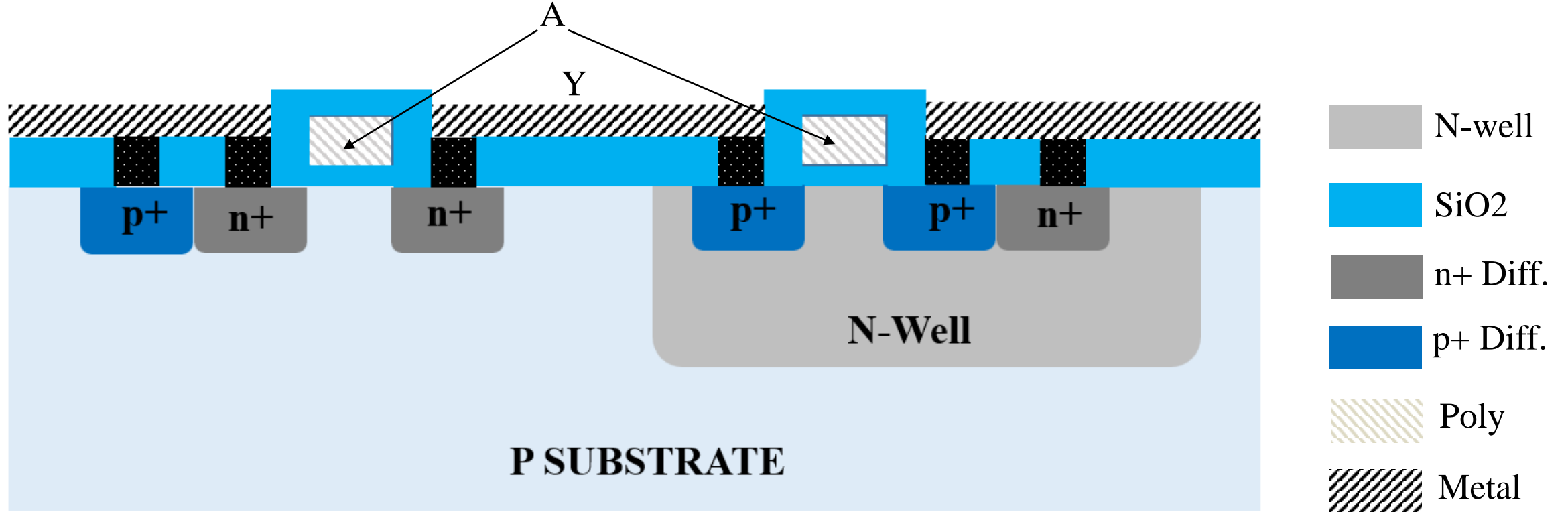
- The final processing step is to add a protective glass layer called passivation or over glass that prevents the ingress of contaminants.
- Openings in the passivation layer, called overglass cuts, allow connection to I/O pads and test probe points if needed.

## **10. Metrology**

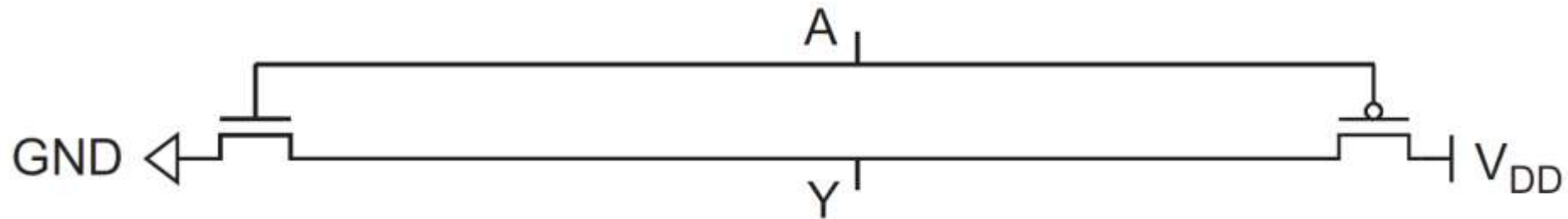
- Metrology is the science of measuring. Everything that is built in a semiconductor process has to be measured to give feedback to the manufacturing process.
- This ranges from simple optical measurements of line widths to advanced techniques to measure thin films and defects such as voids in copper interconnects.

# **CMOS Fabrication Process**

# CMOS Fabrication Process



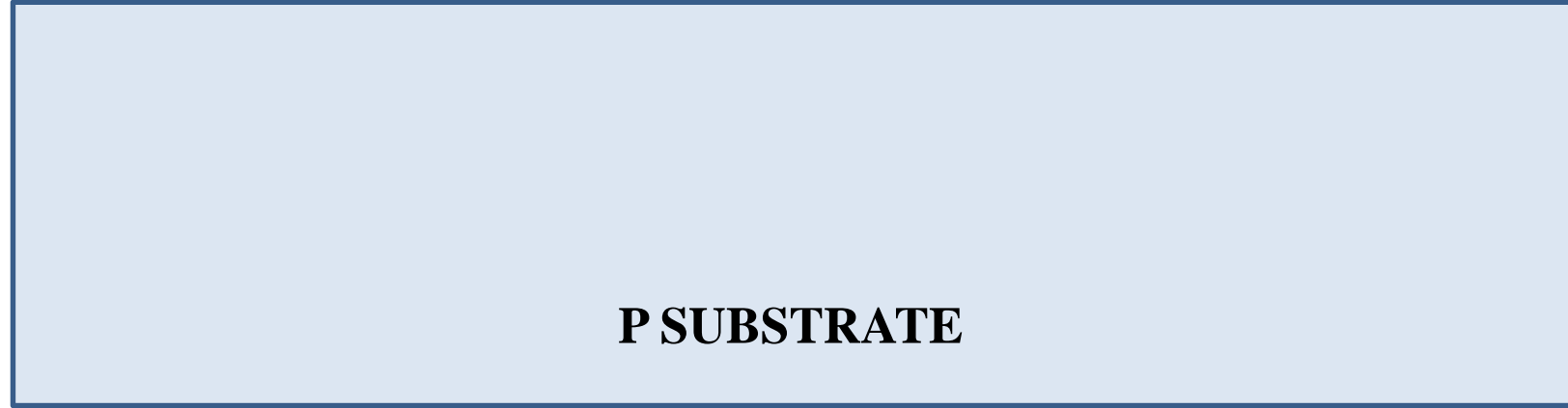
Inverter cross section with well and substrate contact



Inverter Schematic

# CMOS Fabrication Process

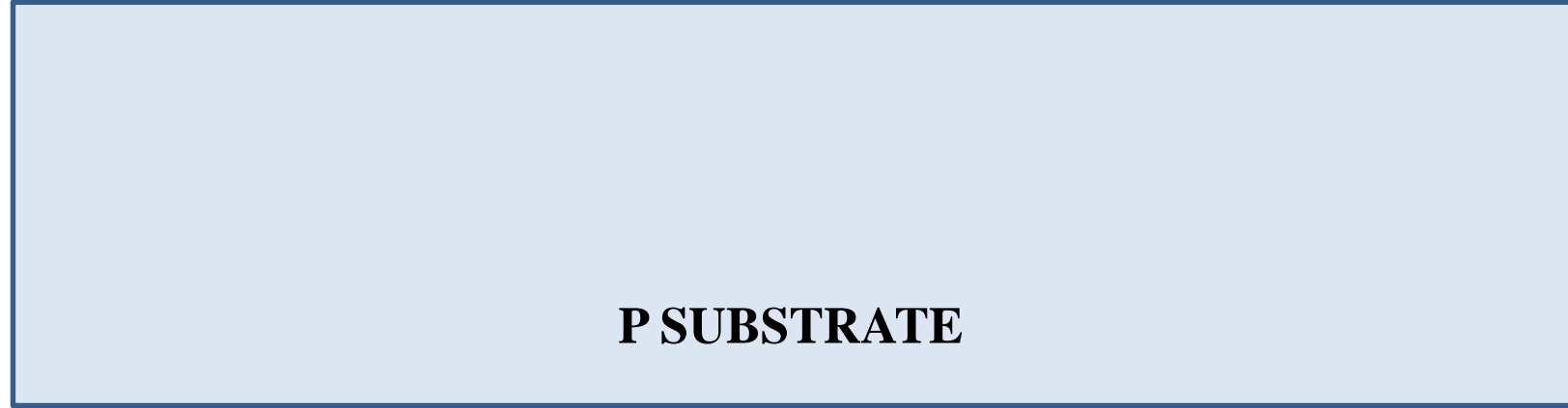
**Substrate Creation**



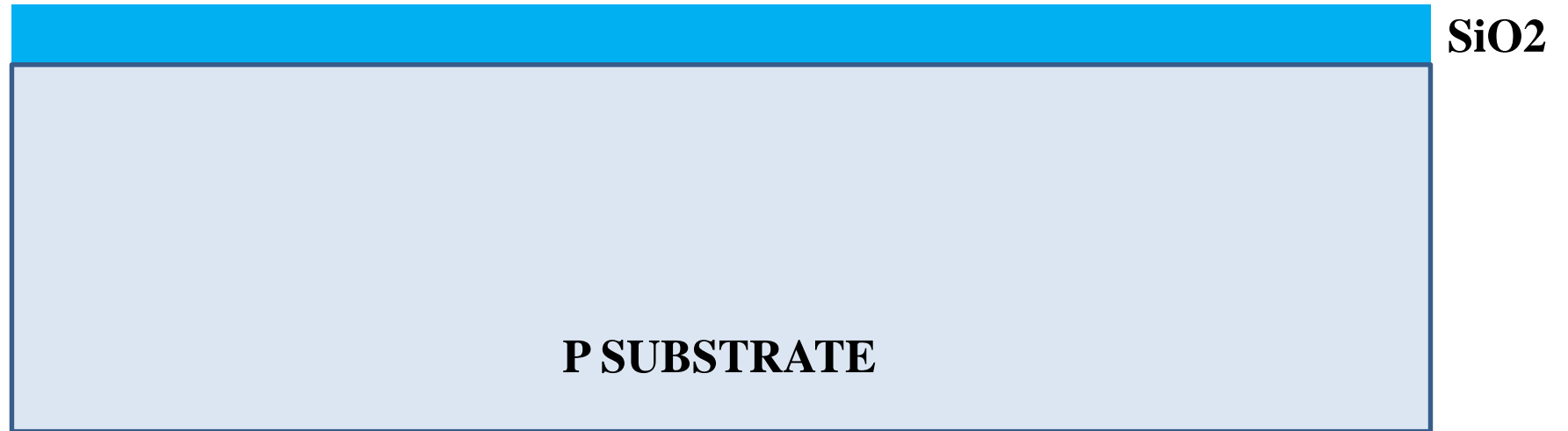


# CMOS Fabrication Process

**Substrate Creation**

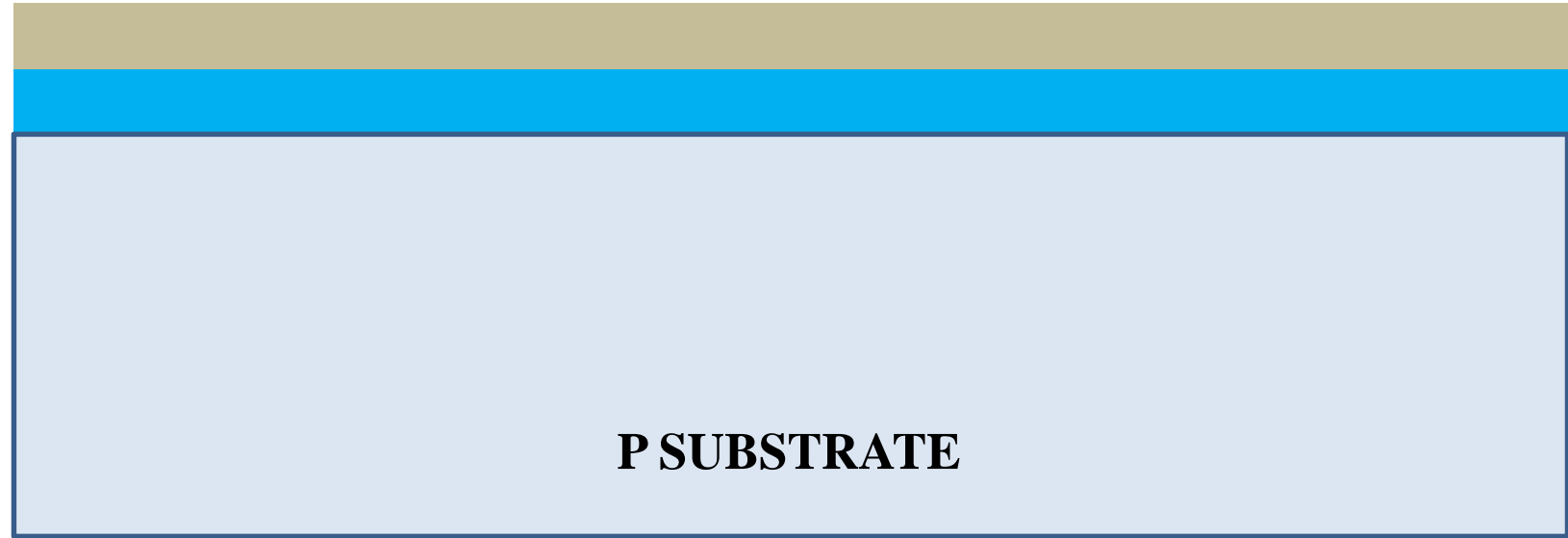


**Deposition of  
protective SiO<sub>2</sub>**



# CMOS Fabrication Process

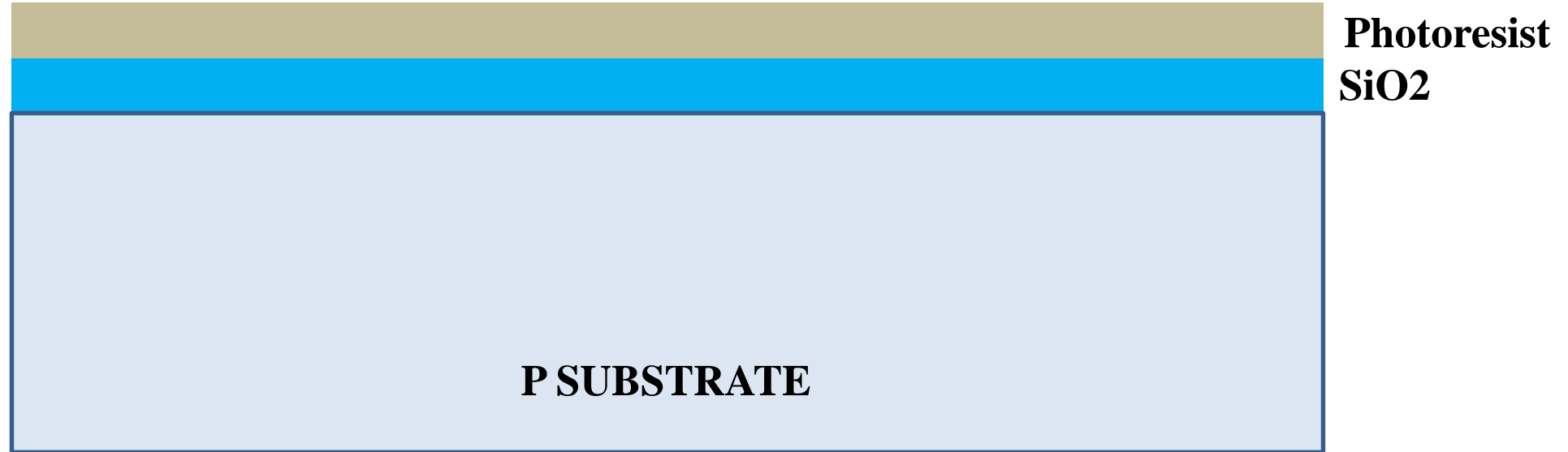
**Deposition of  
photoresist material**



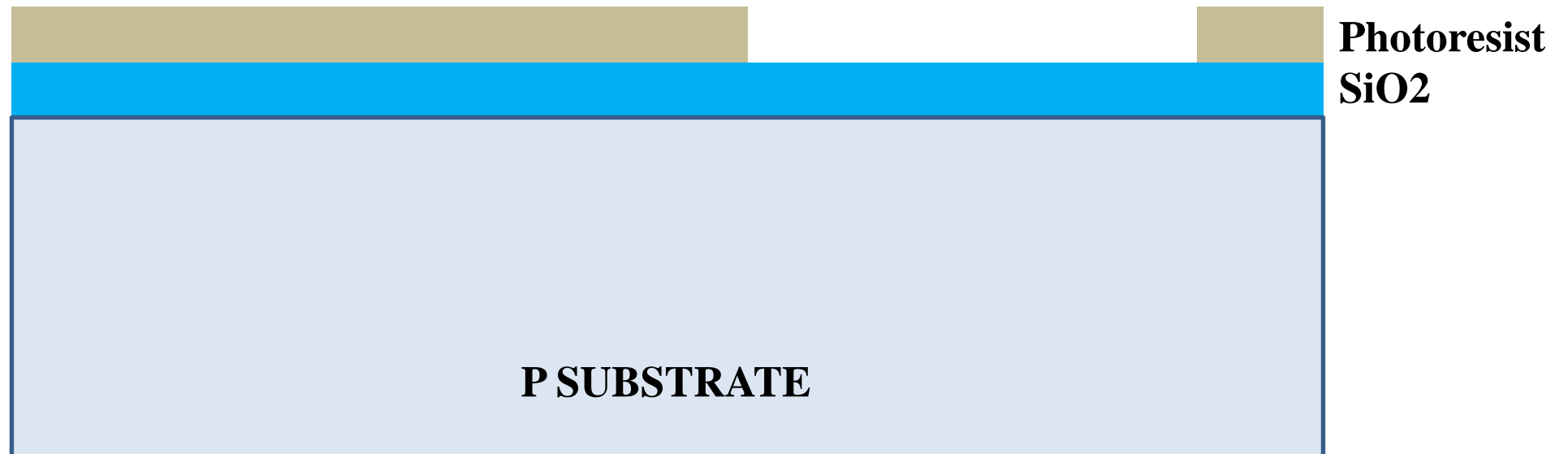
**Photoresist  
SiO2**

# CMOS Fabrication Process

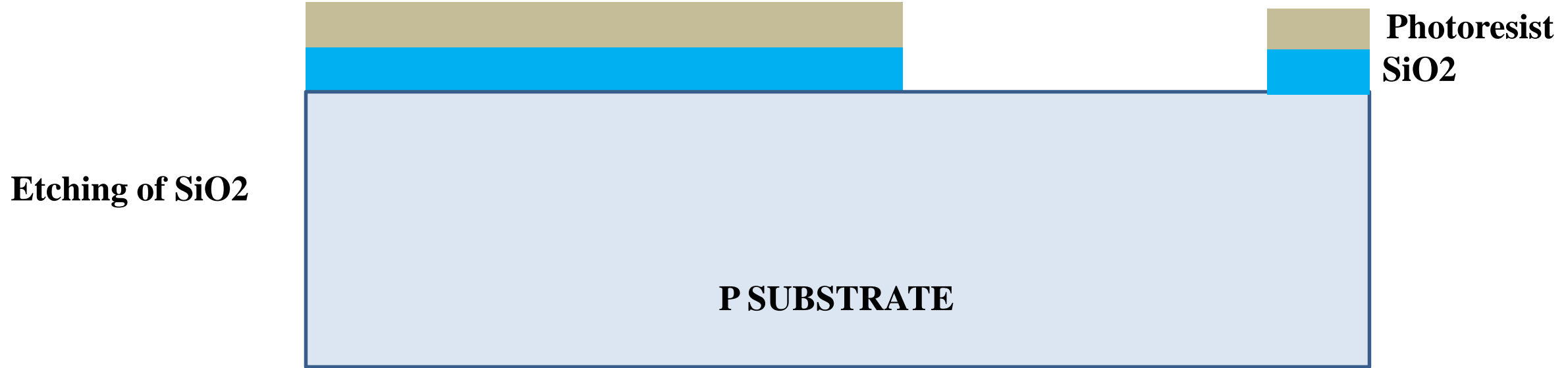
**Deposition of  
photoresist material**



**Etching of  
photoresist material**

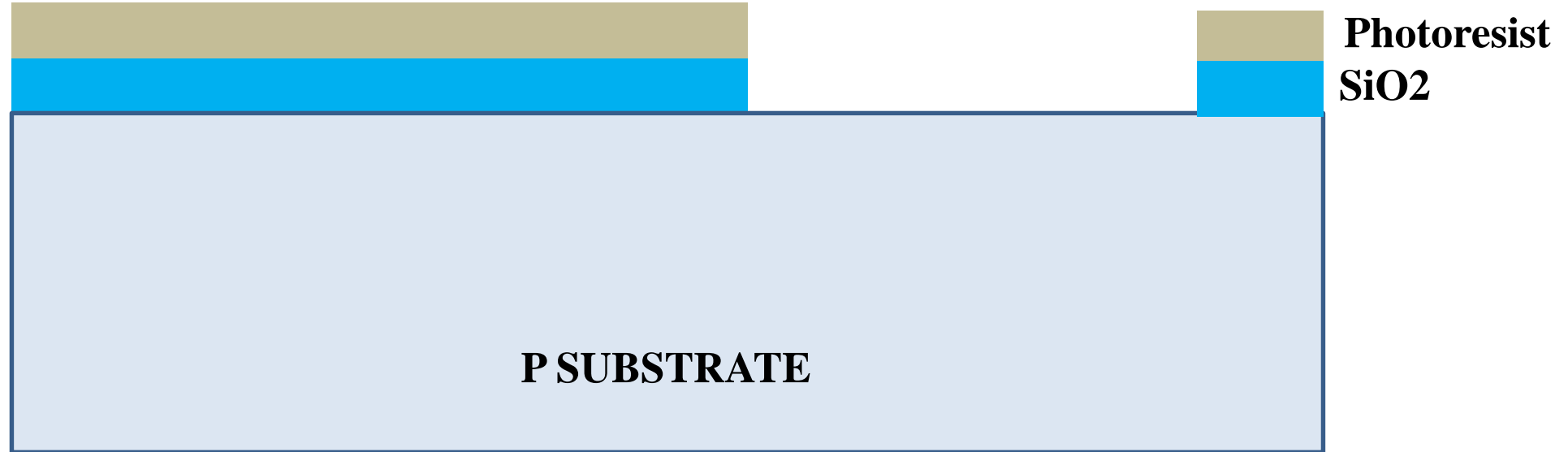


# CMOS Fabrication Process

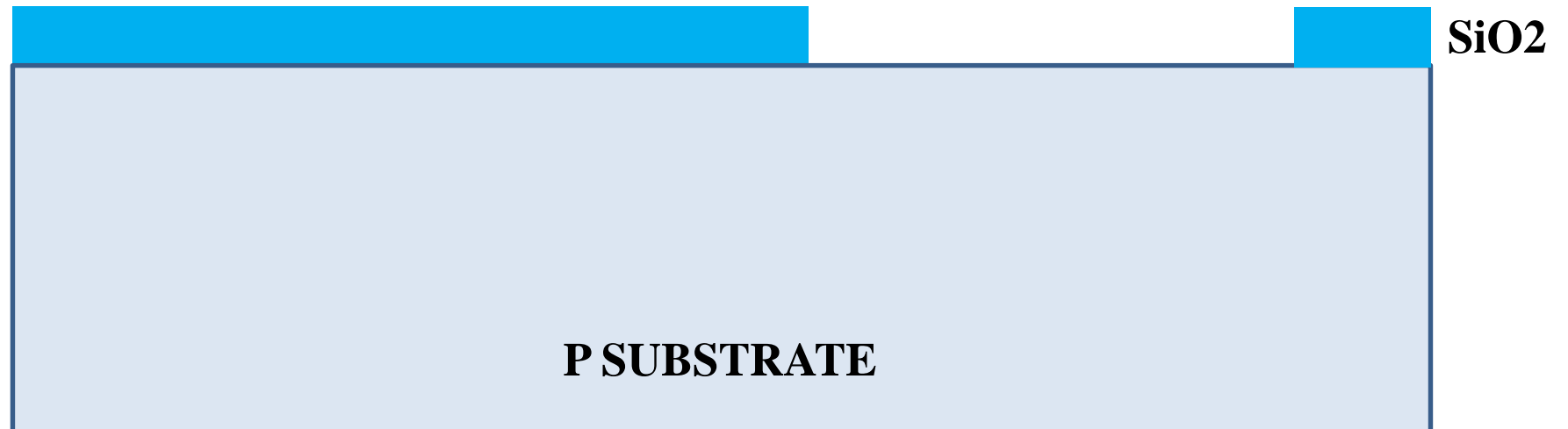


# CMOS Fabrication Process

**Etching of SiO<sub>2</sub>**

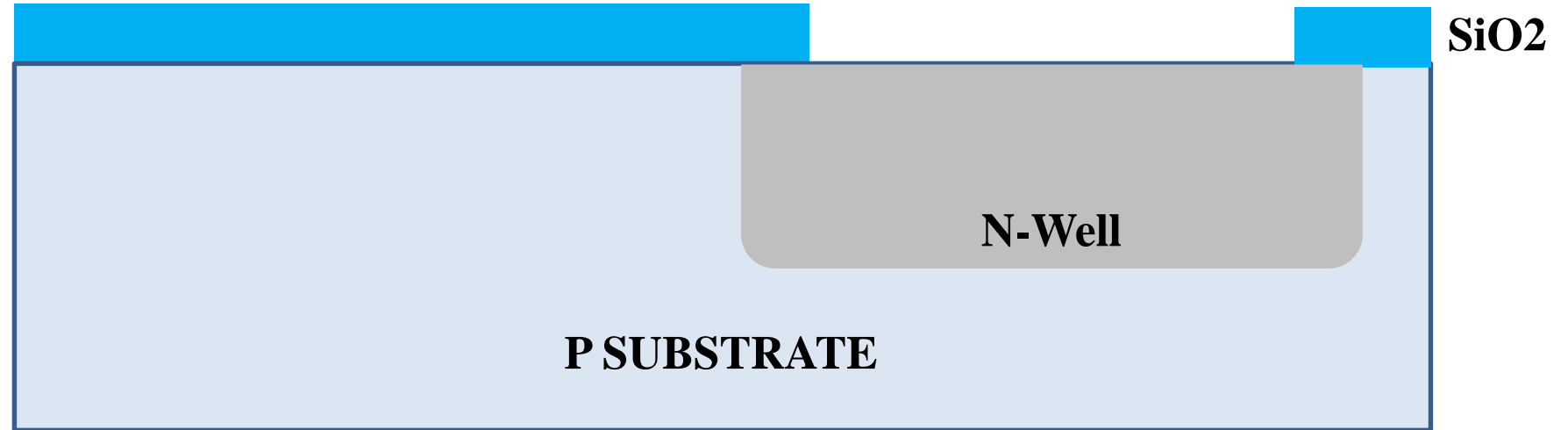


**Complete Etching of  
photoresist material**



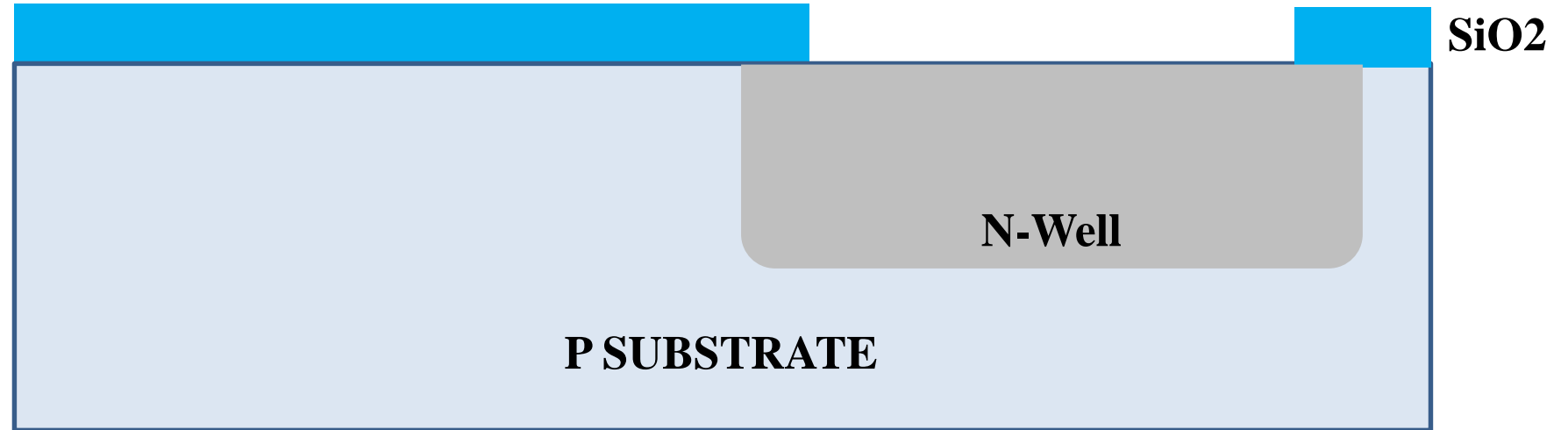
# CMOS Fabrication Process

**N-well Creation**

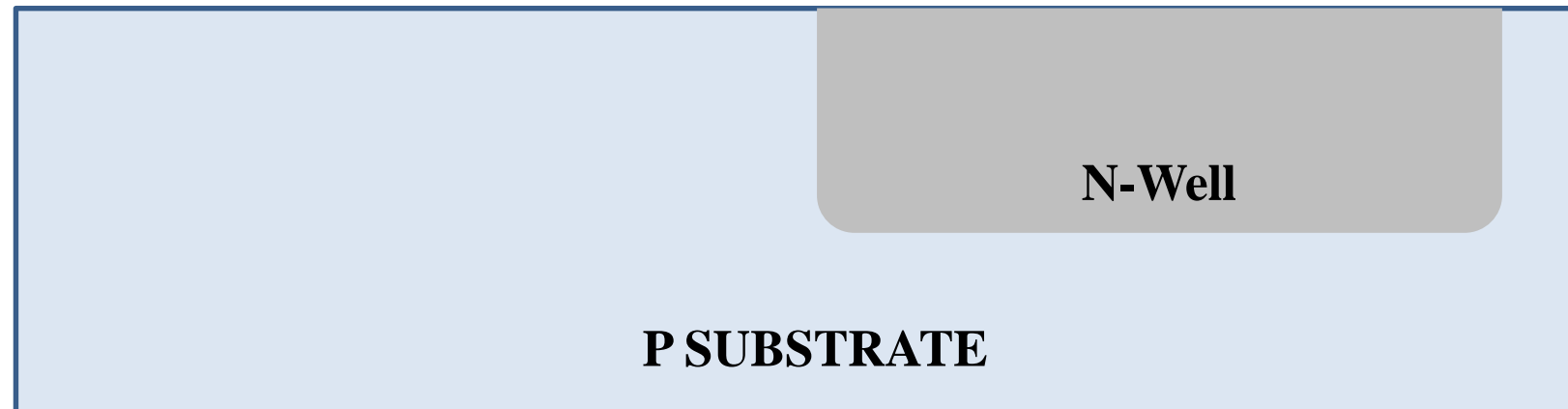


# CMOS Fabrication Process

**N-well Creation**

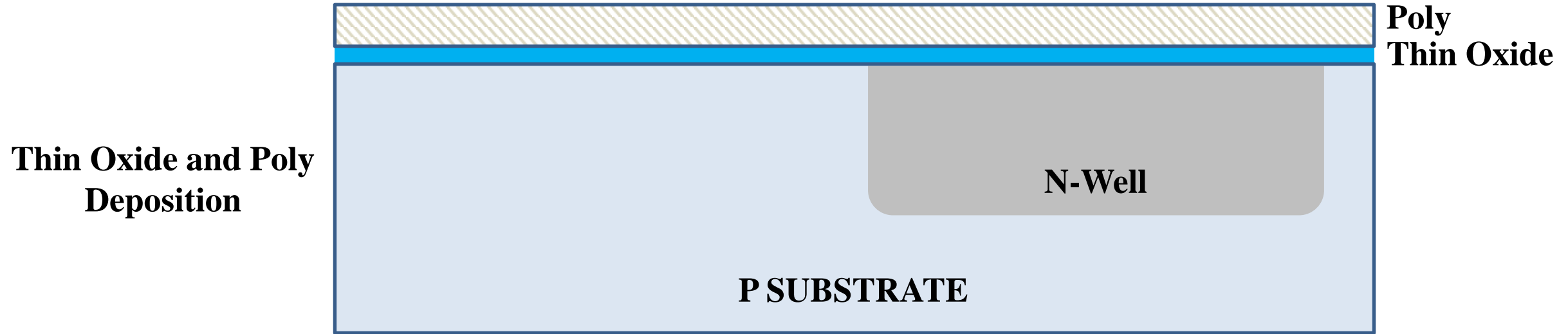


**Etching of SiO2**



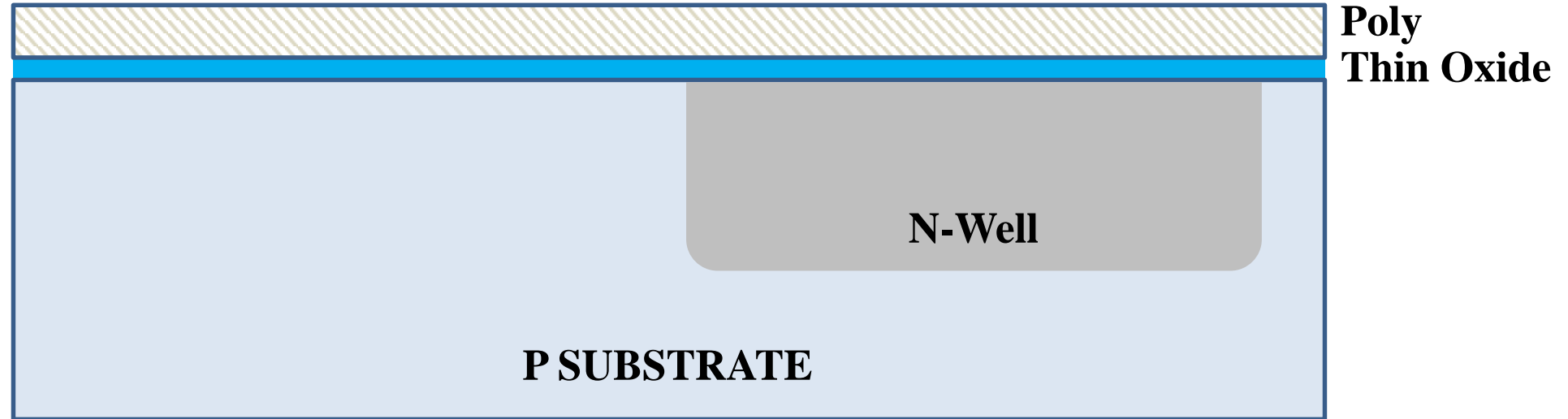


# CMOS Fabrication Process

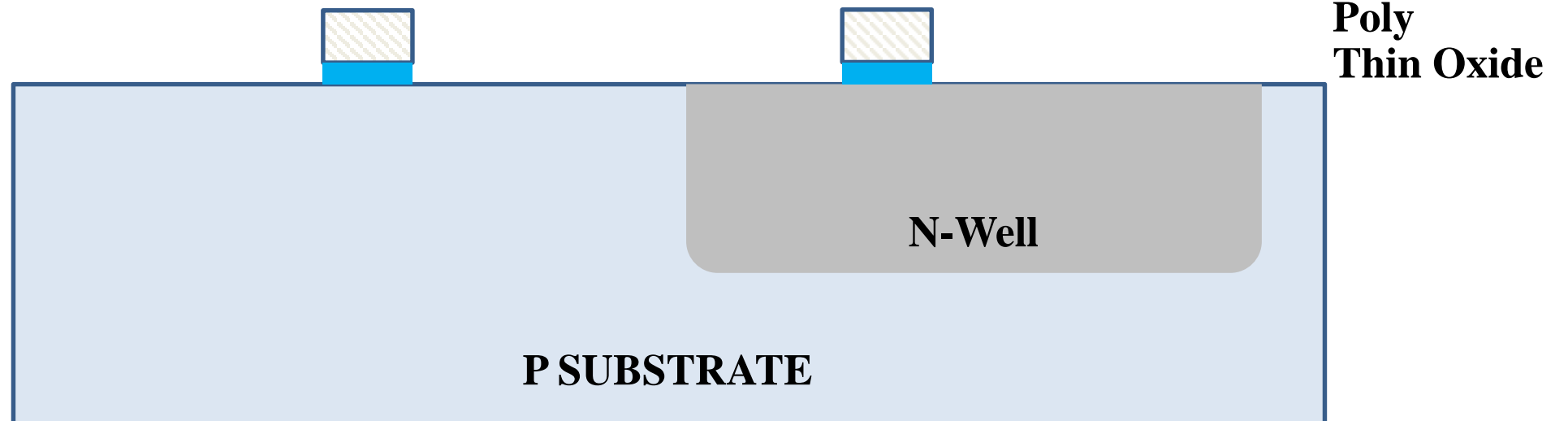


# CMOS Fabrication Process

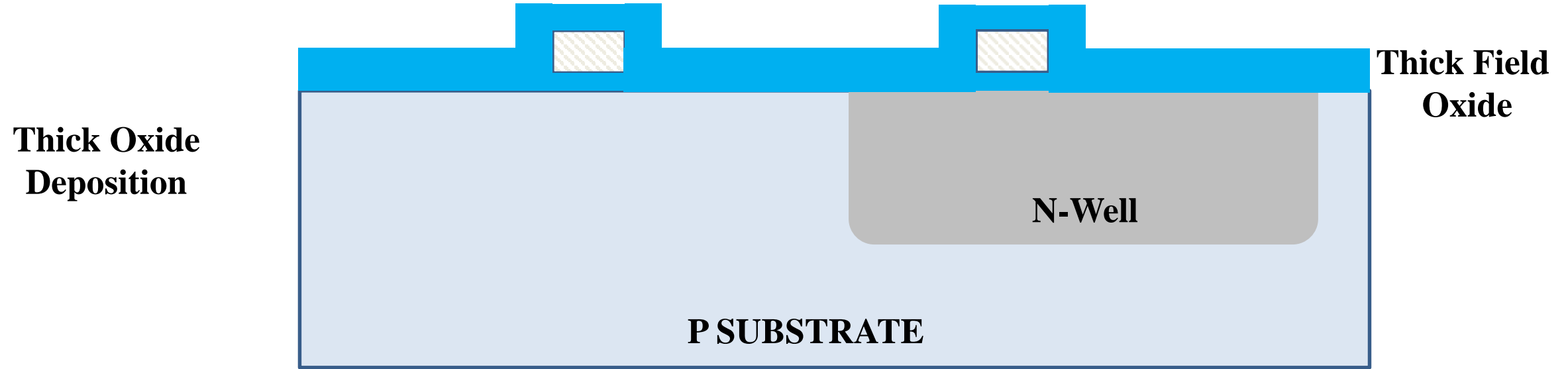
**Thin Oxide and Poly  
Deposition**



**Etching of Thin  
Oxide and poly  
except the gate region**

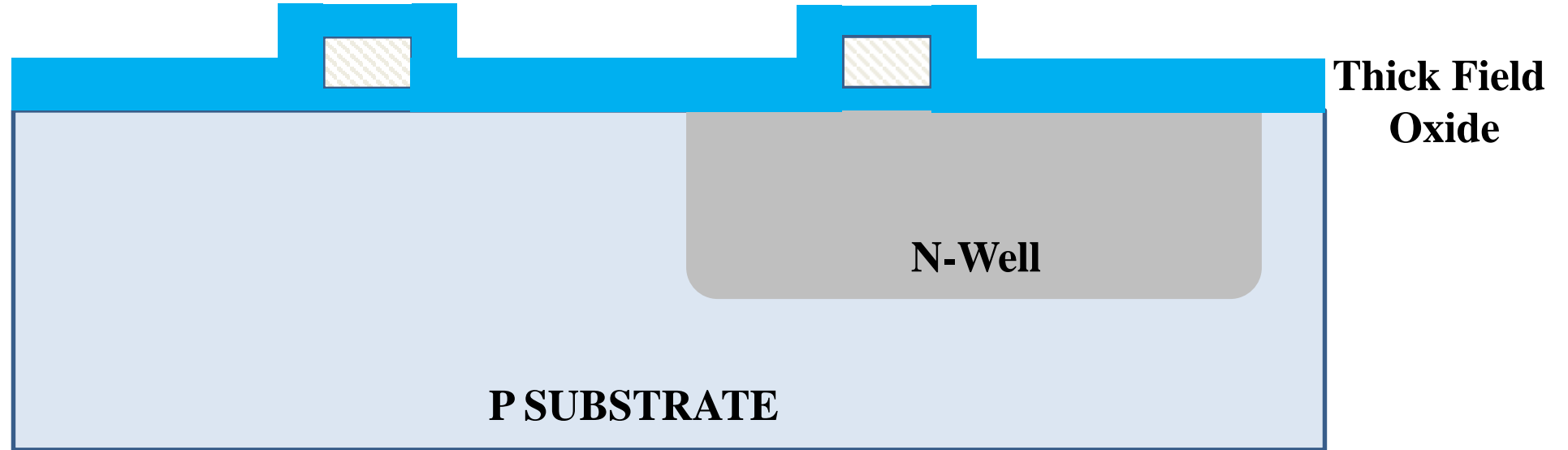


# CMOS Fabrication Process

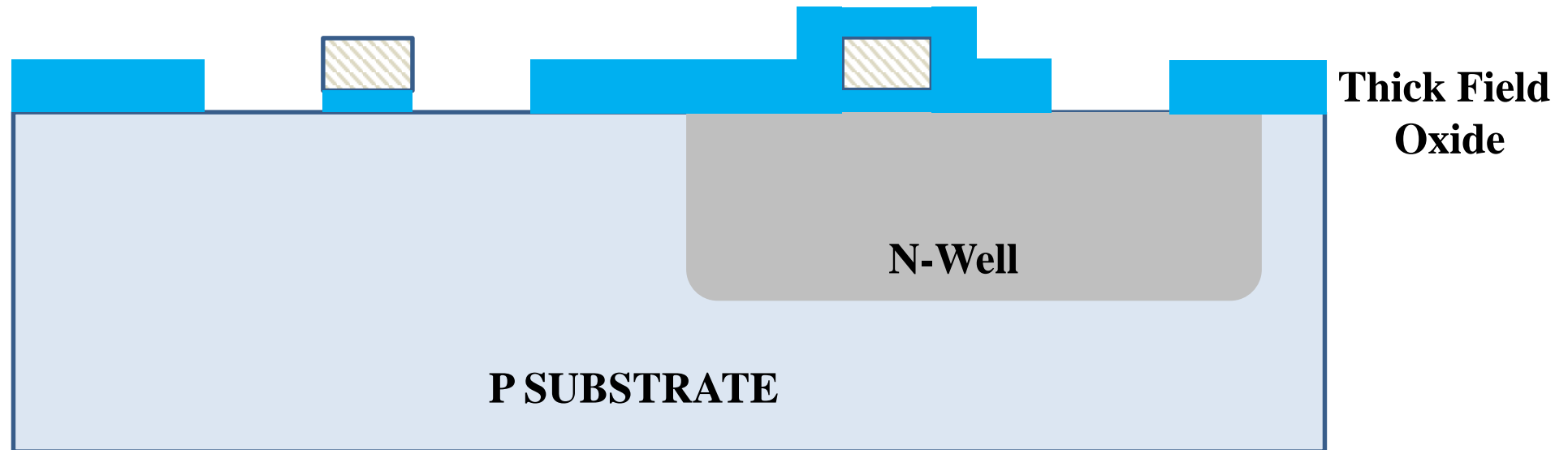


# CMOS Fabrication Process

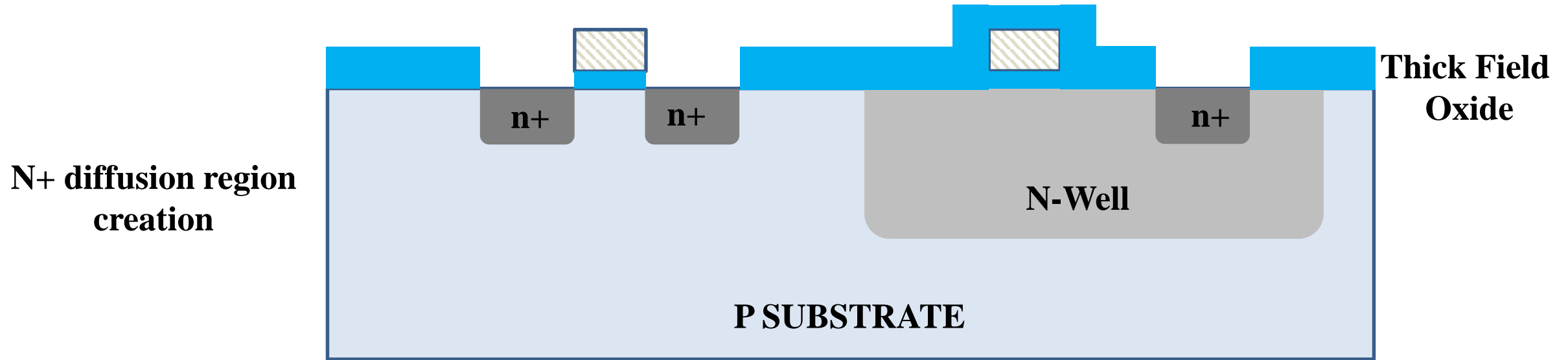
**Thick Oxide  
Deposition**



**Etching of Thick  
Oxide**

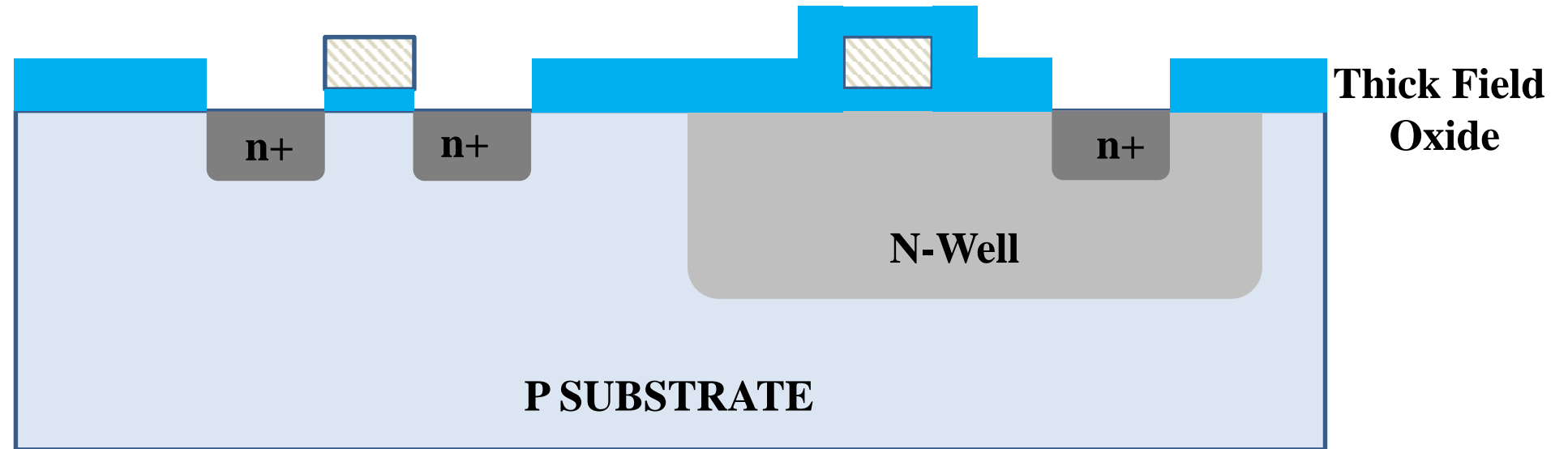


# CMOS Fabrication Process

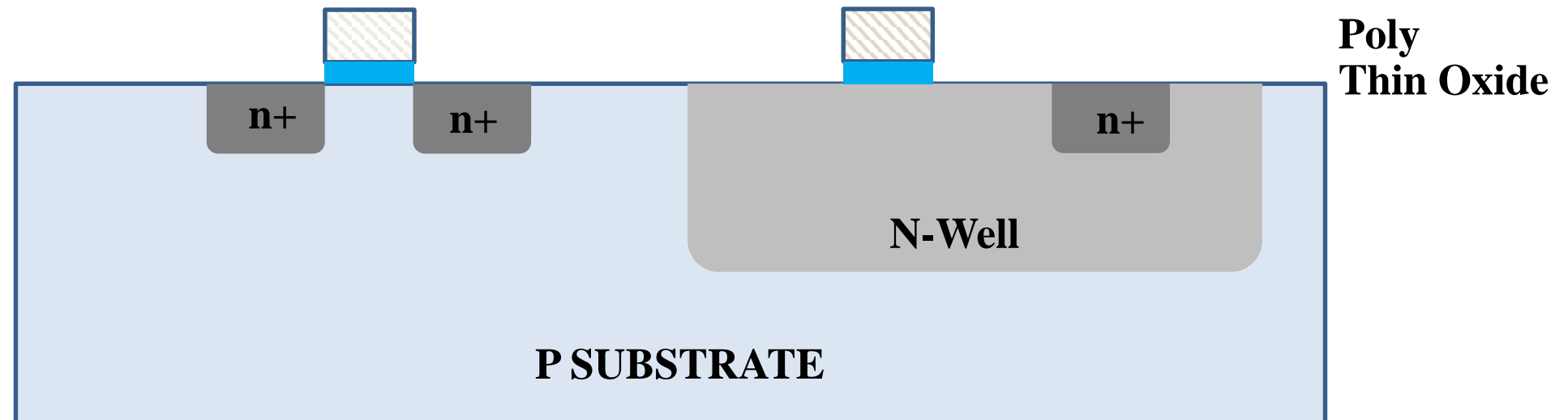


# CMOS Fabrication Process

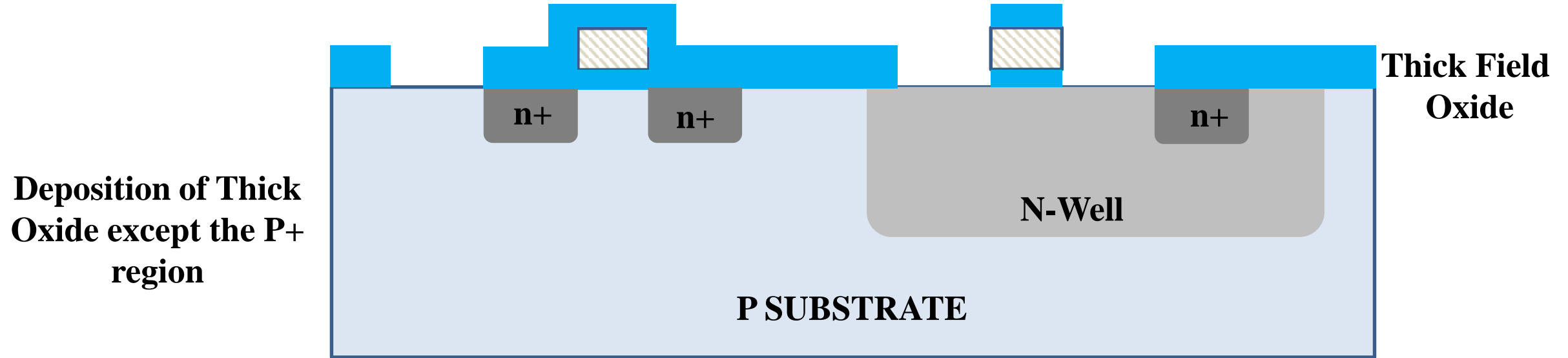
**N+ diffusion region  
creation**



**Etching of Thick  
Oxide**



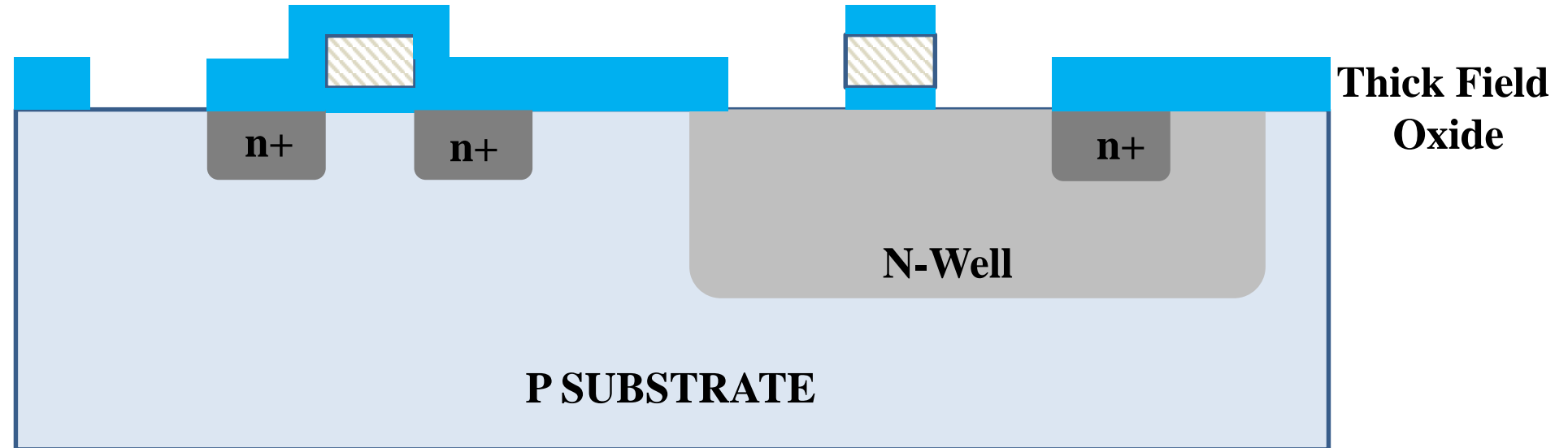
# CMOS Fabrication Process



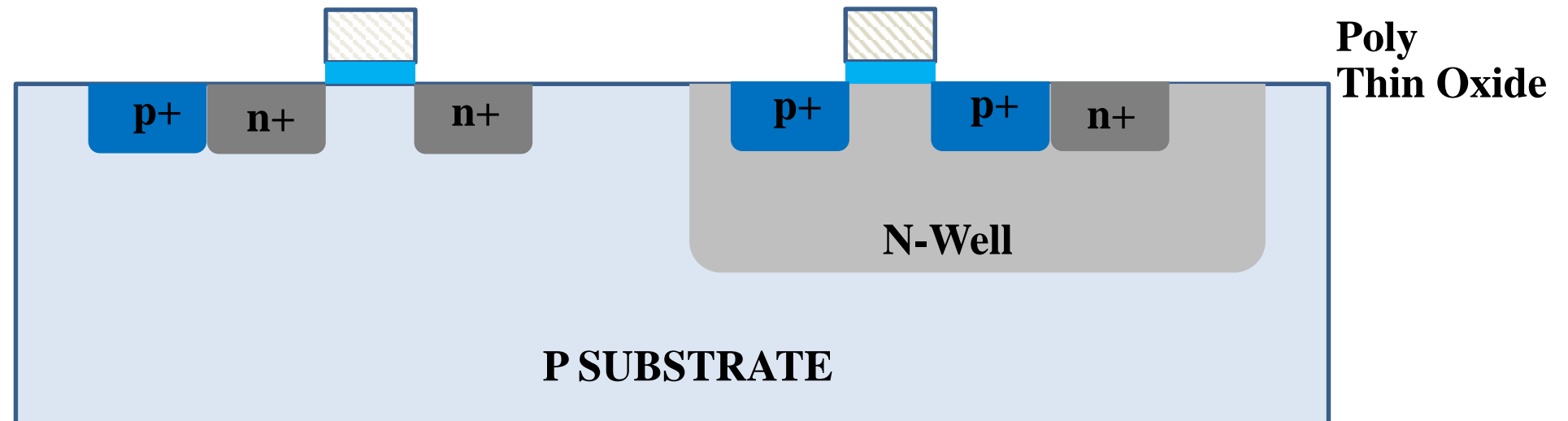


# CMOS Fabrication Process

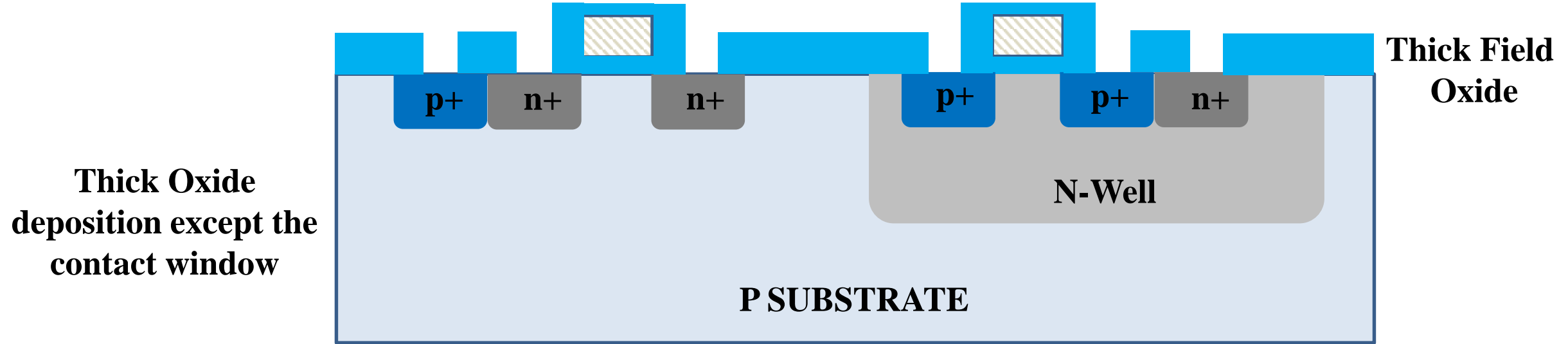
Deposition of Thick  
Oxide except the P+  
region



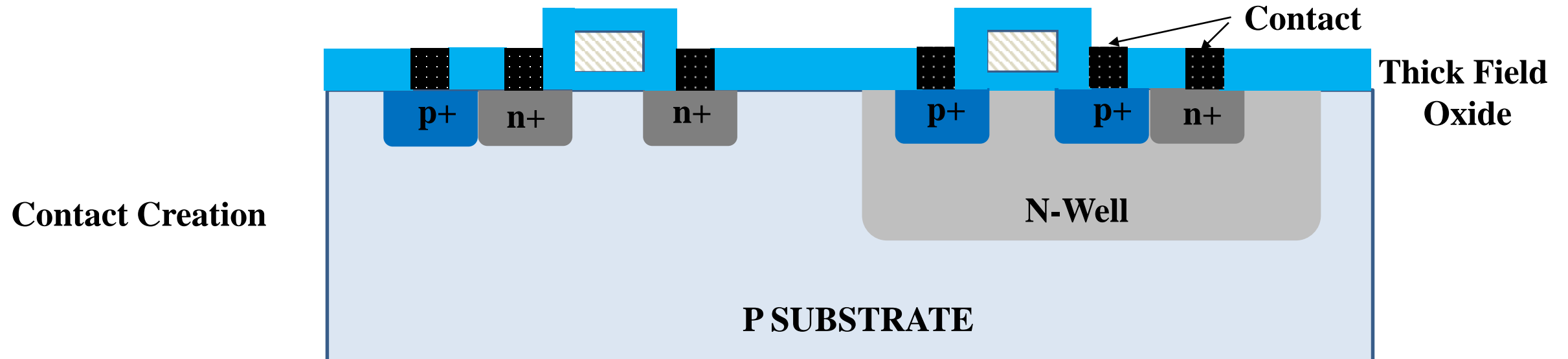
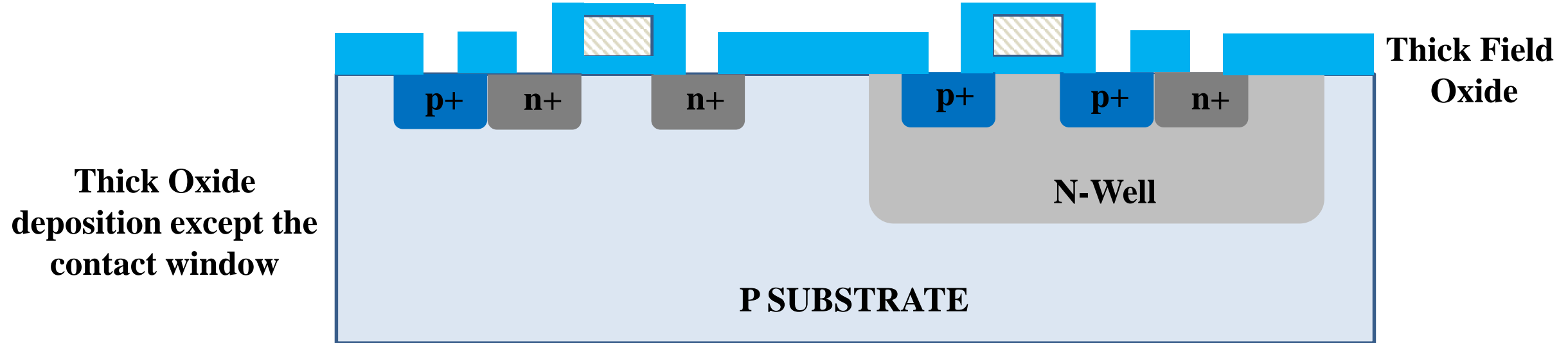
P+ region creation



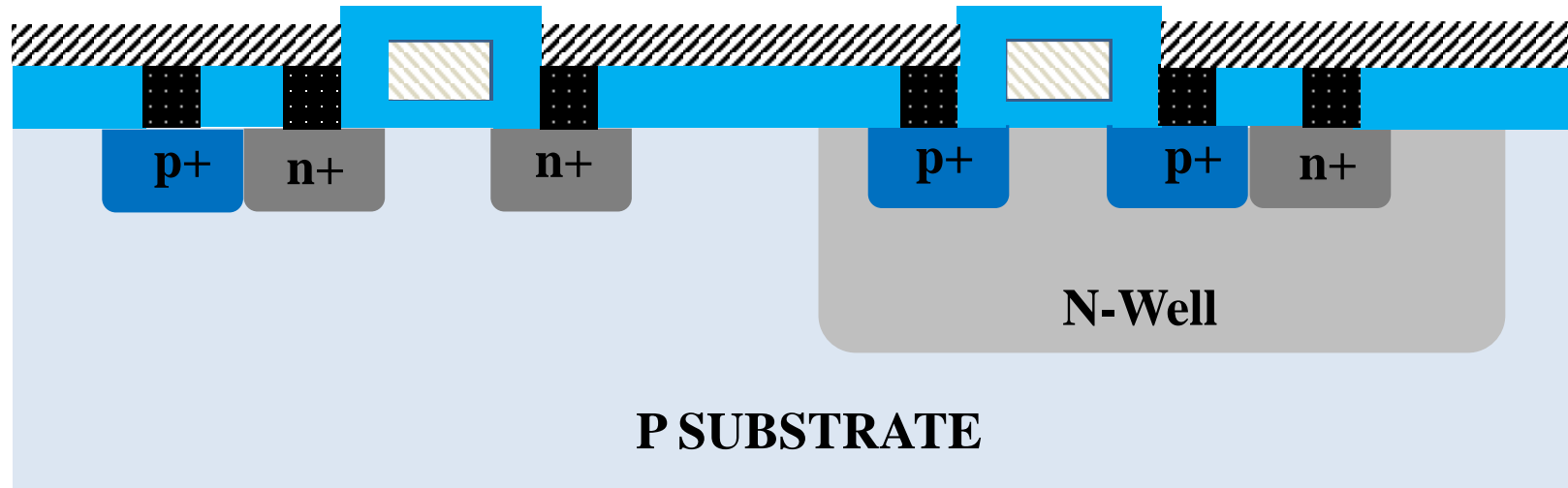
# CMOS Fabrication Process



# CMOS Fabrication Process



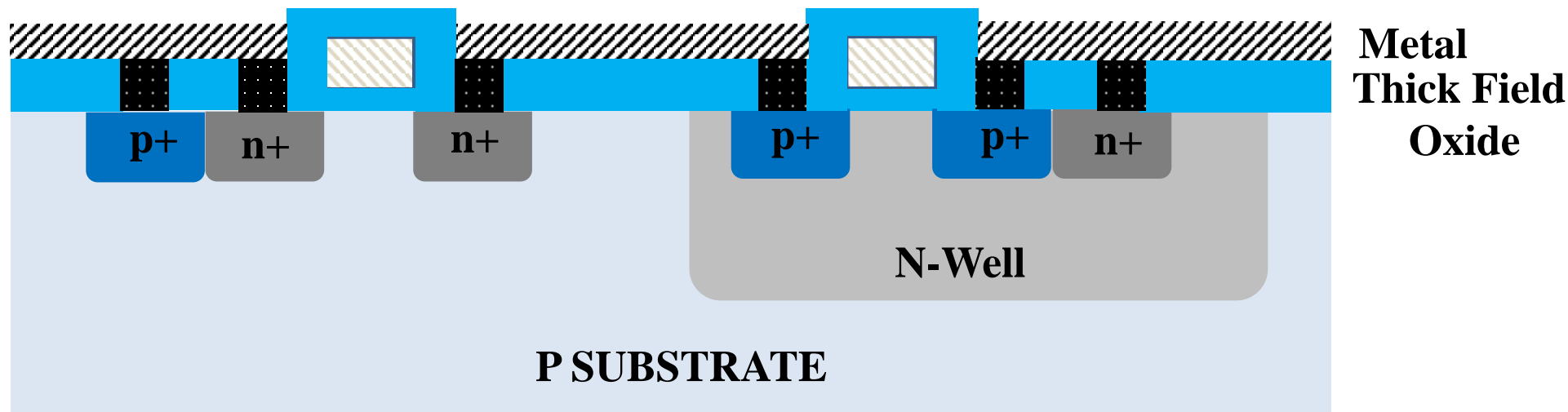
# CMOS Fabrication Process



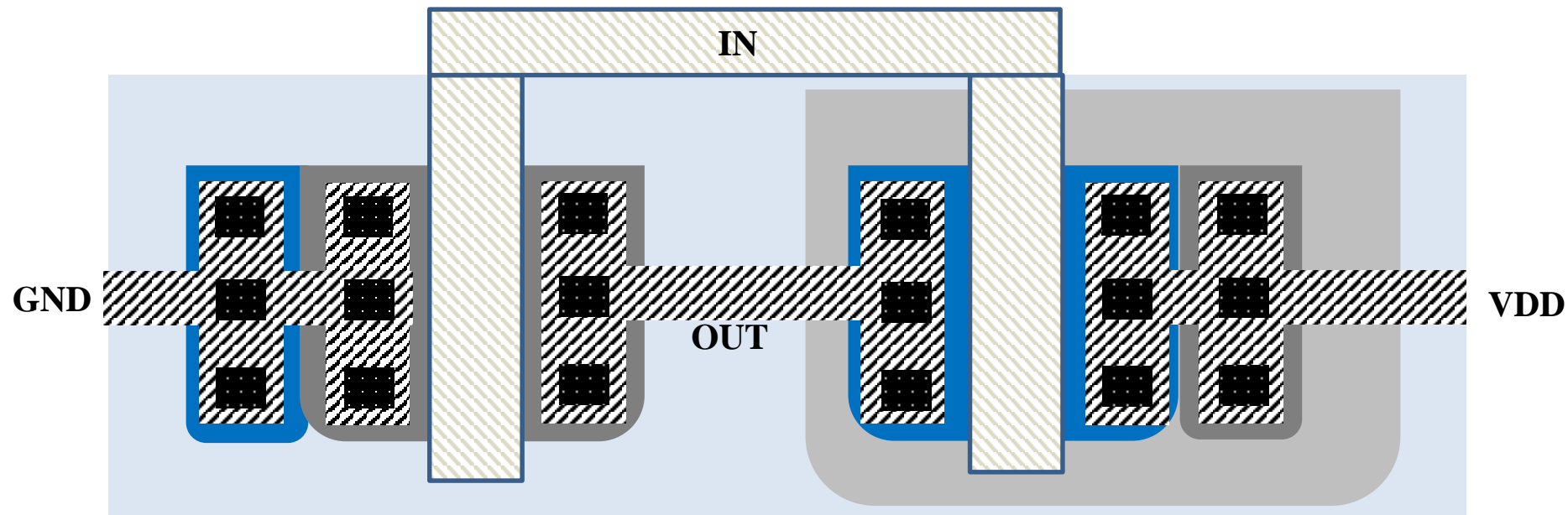
**Metal Deposition**

**Metal  
Thick Field  
Oxide**

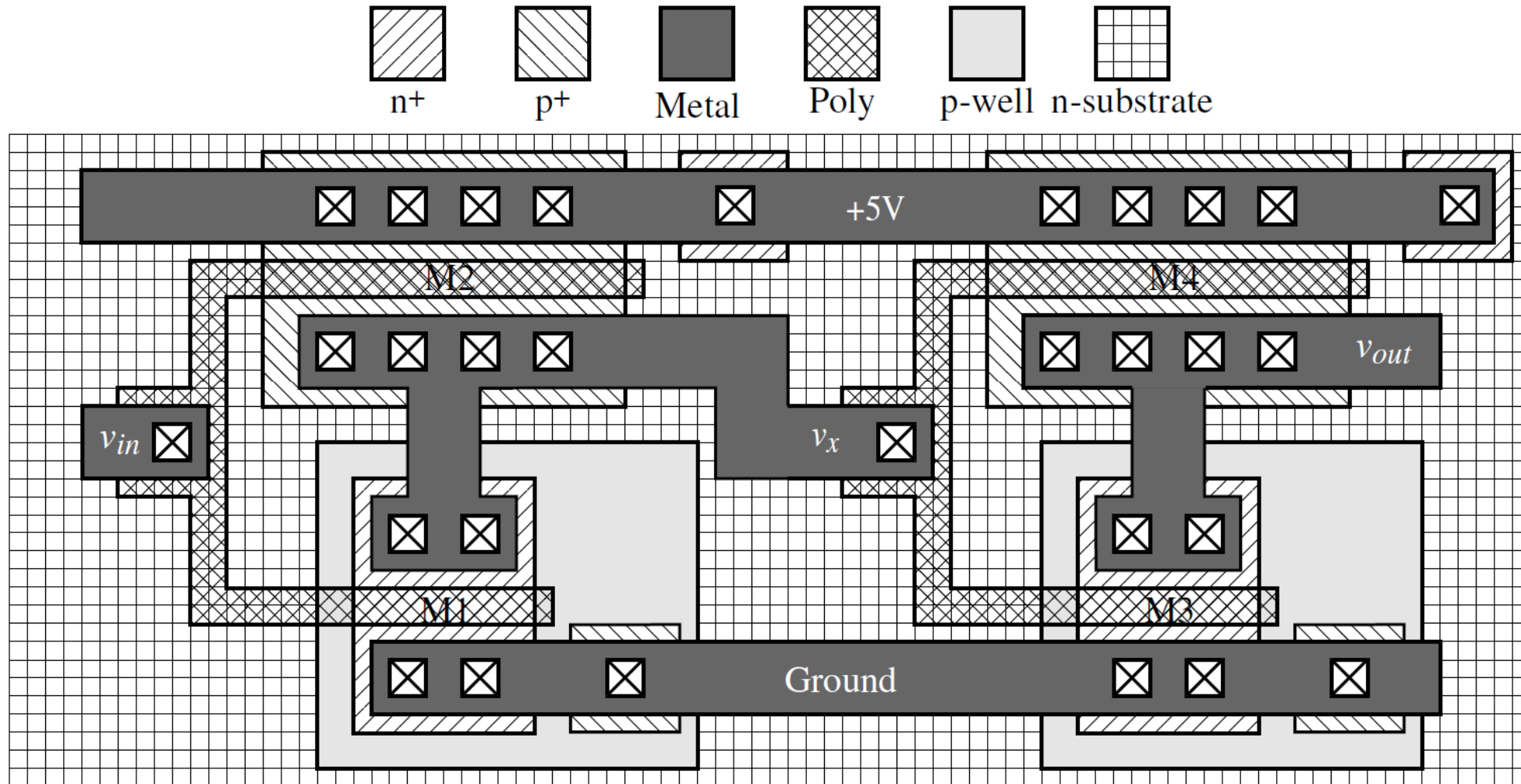
# CMOS Fabrication Process



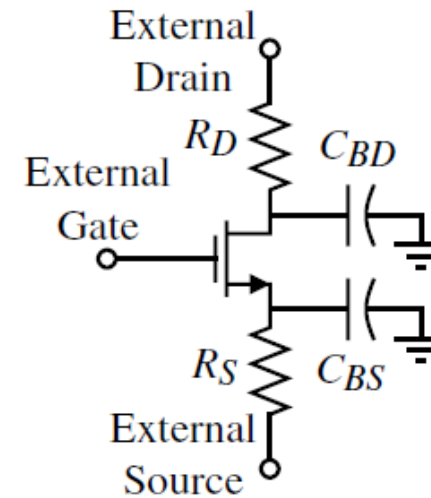
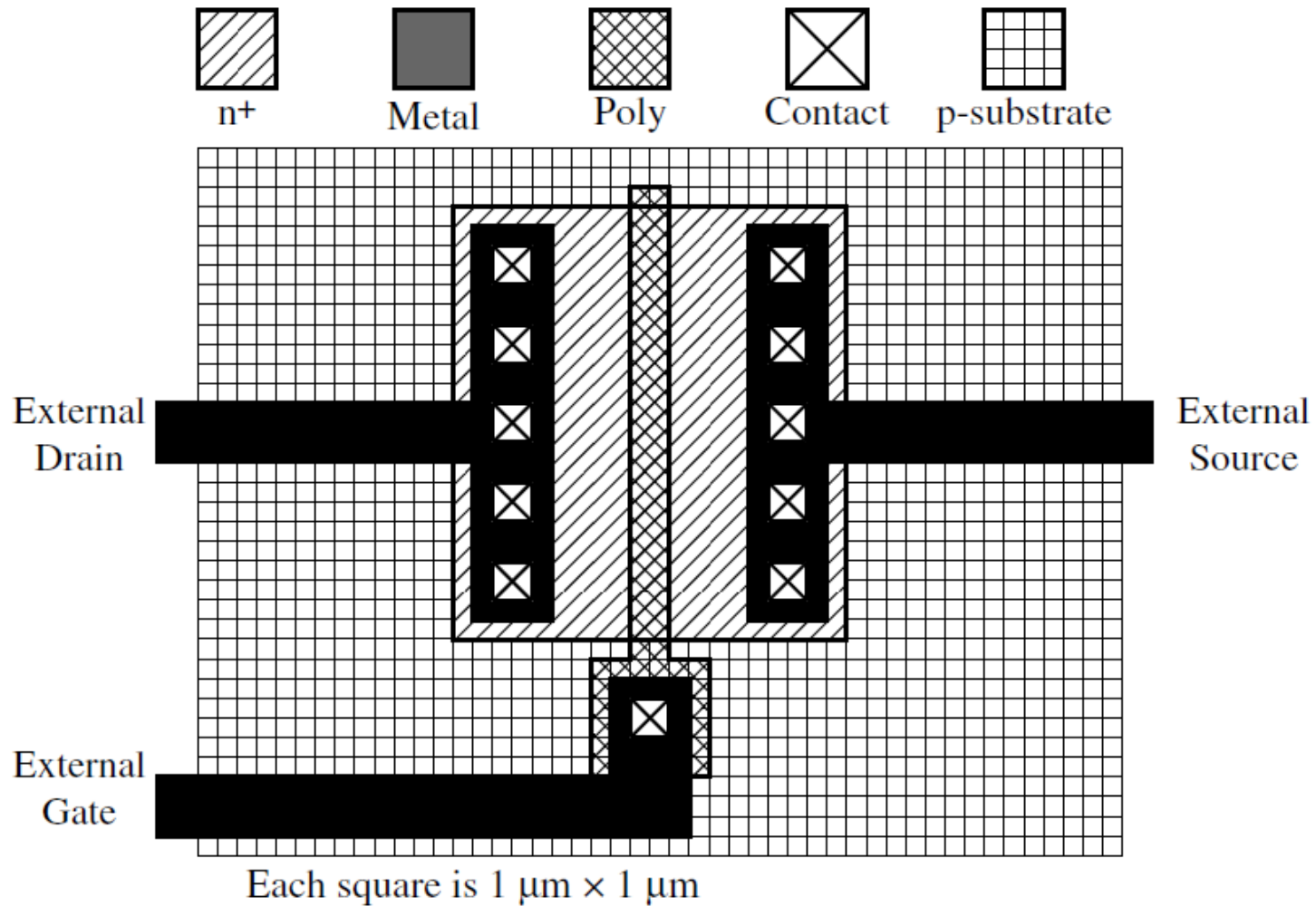
**Layout**



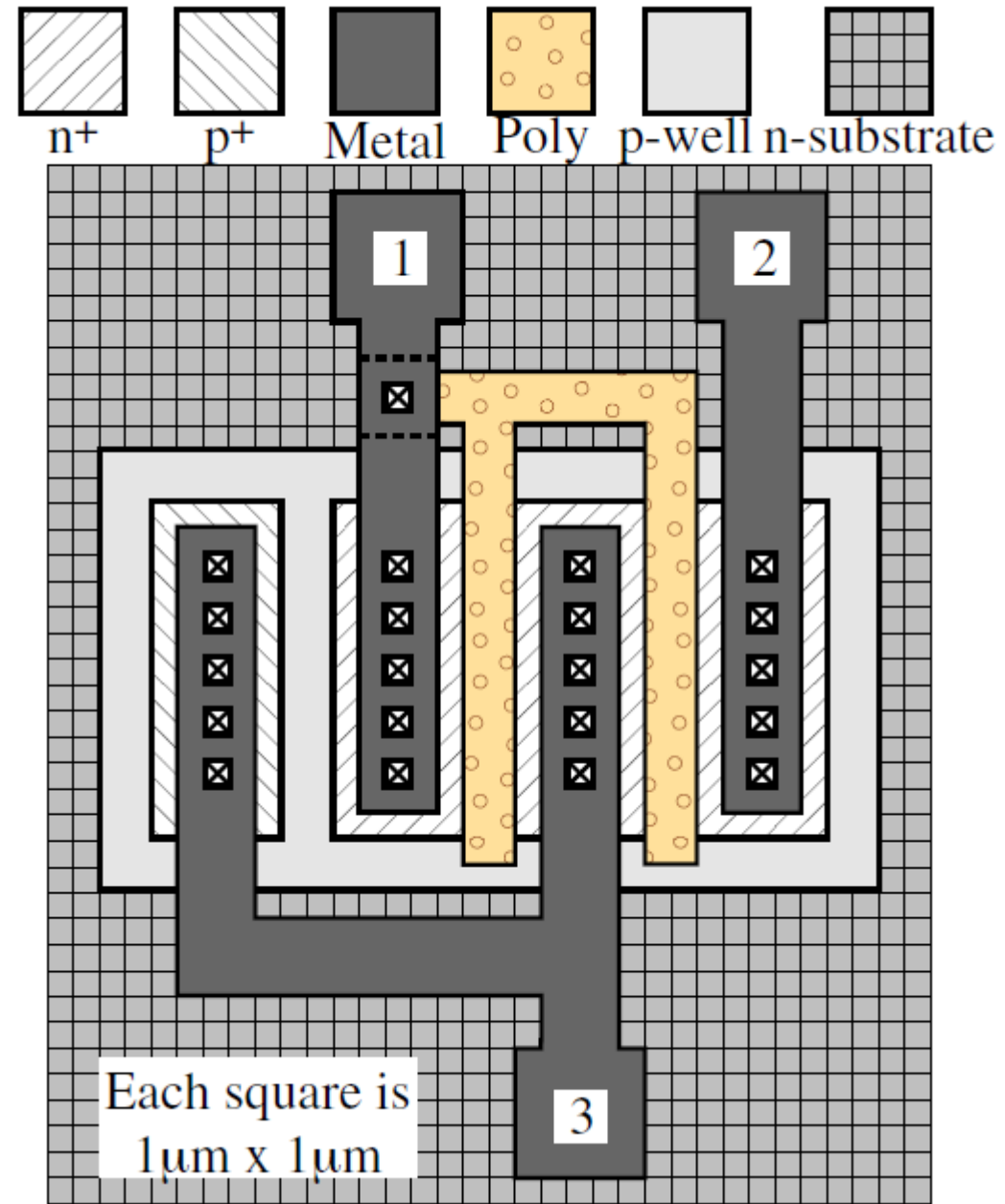
# Layout Exercises



# Layout Exercises

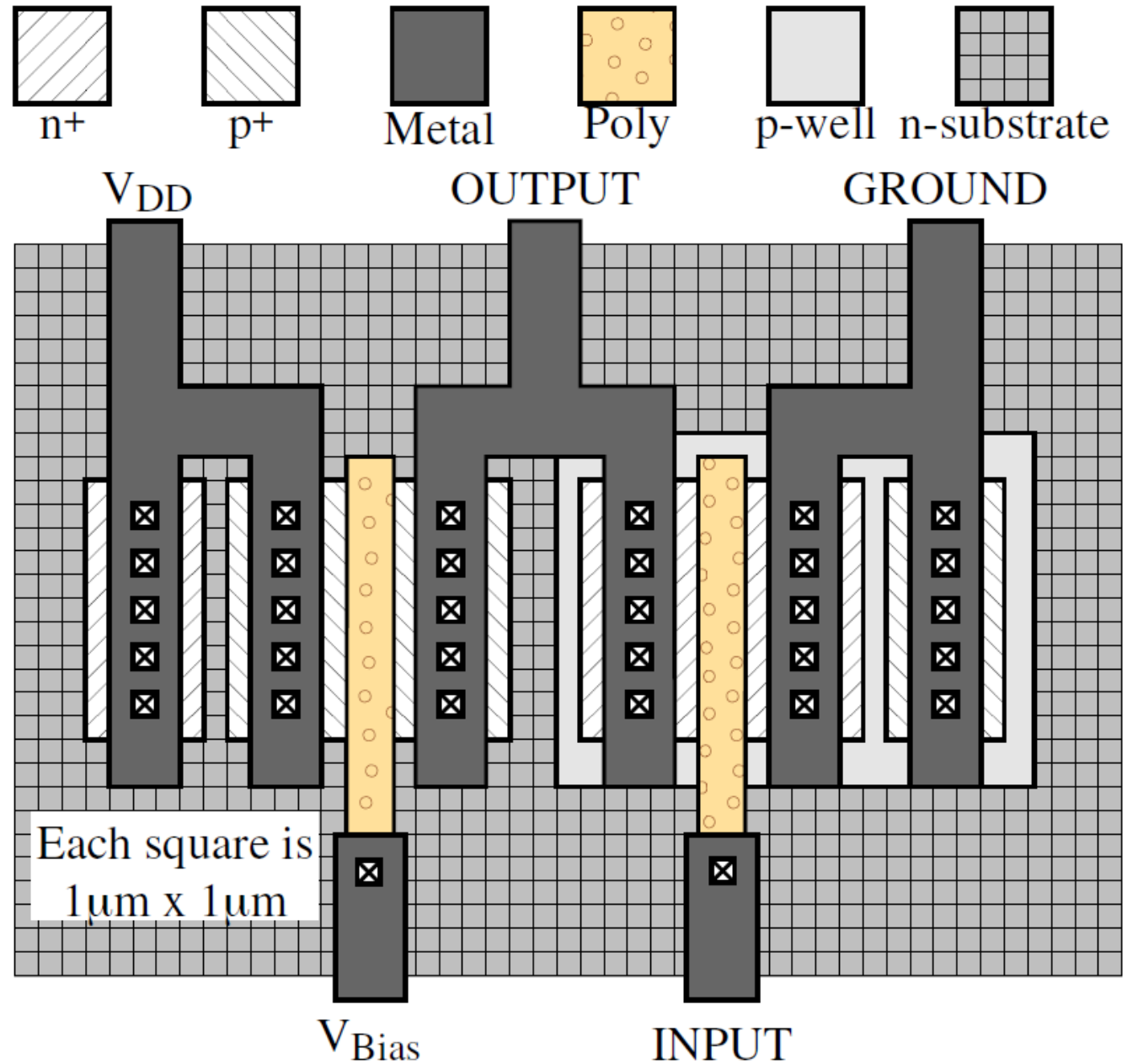


# Layout Exercises

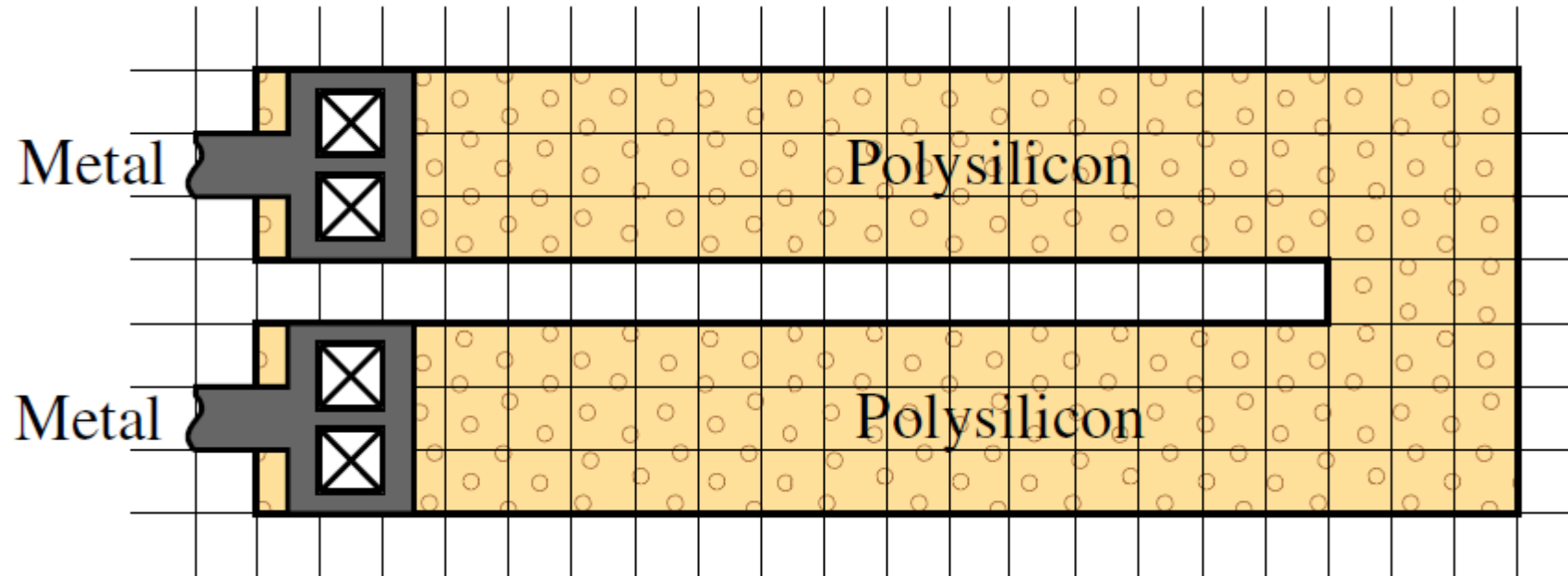




# Layout Exercises



# Layout Exercises



**Thank You**